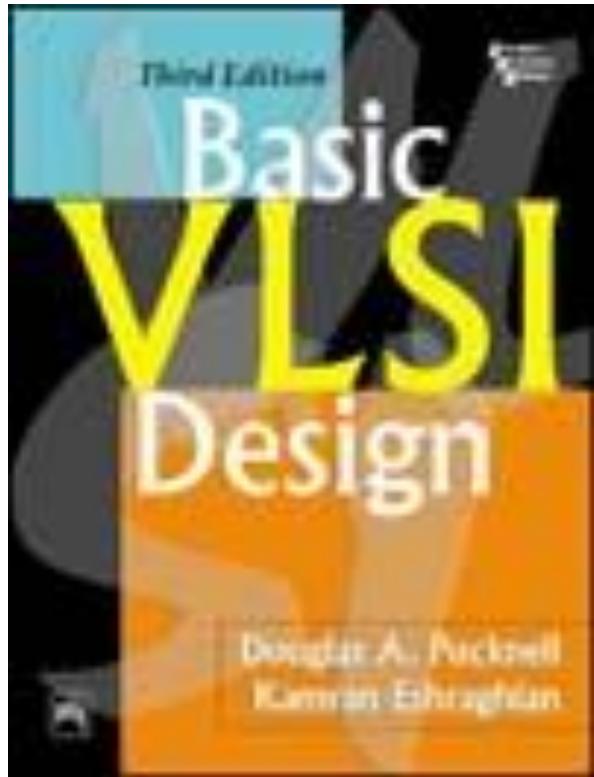
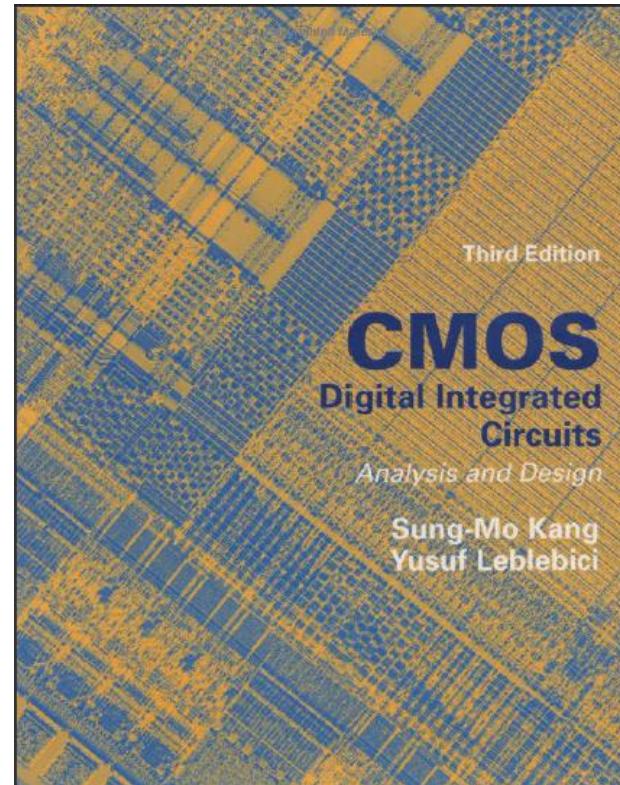


# VLSI Design

# Reference Books

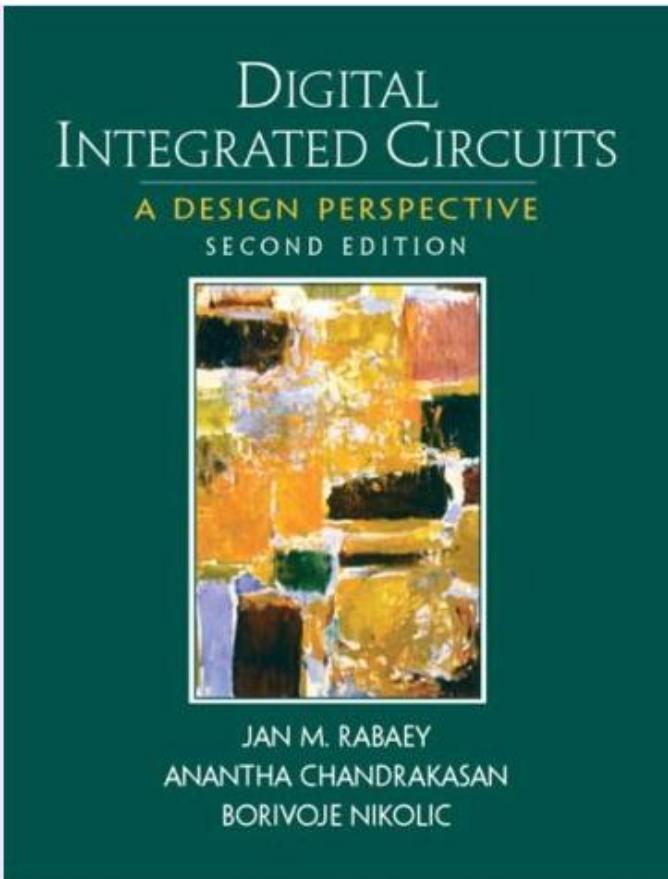


**"Basic VLSI Design", 3<sup>rd</sup> Ed., PHI**  
**By: PUCKNELL DOUGLAS A.ESHRAGHIAN,**  
**KAMRAN**

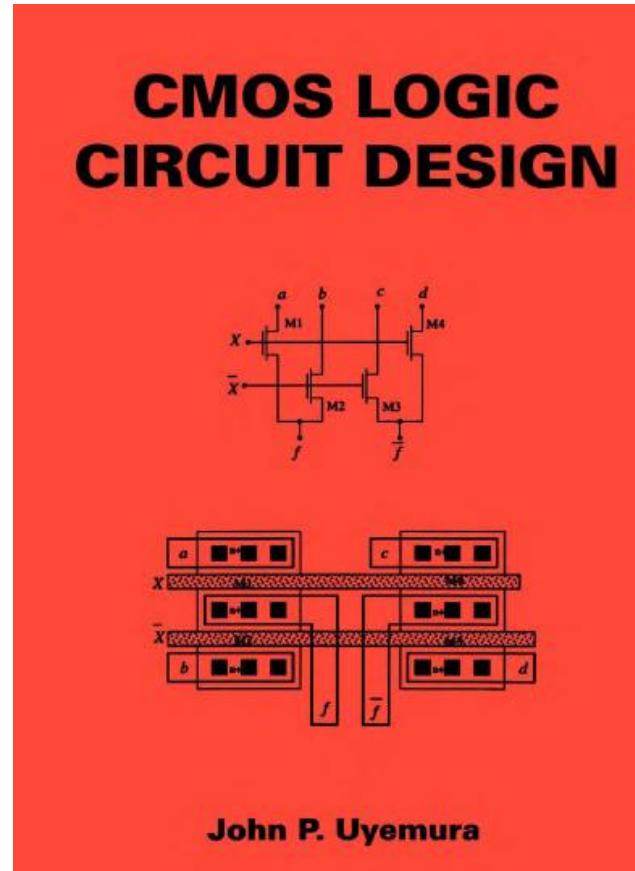


**"CMOS DIGITAL INTEGRATED CIRCUITS:Analysis and Design"**  
**3<sup>rd</sup> Ed. McGraw-Hill.**  
**By:SUNG-MO (STEVE) KANG**

# Reference Books

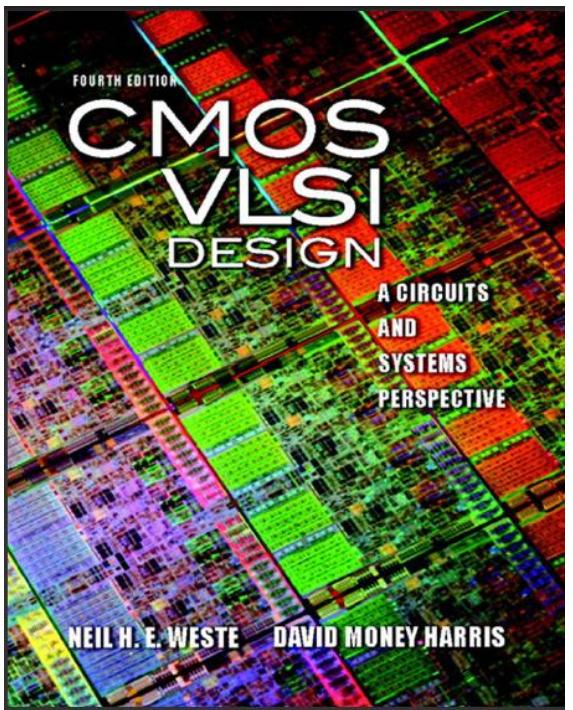


Digital Integrated Circuits – A Design Perspective”,  
2nd ed. by J. Rabaey, A. Chandrakasan, B. Nikolic



“CMOS LOGIC CIRCUIT DESIGN”  
KLUWER ACADEMIC PUBLISHERS  
By: John P. Uyemura

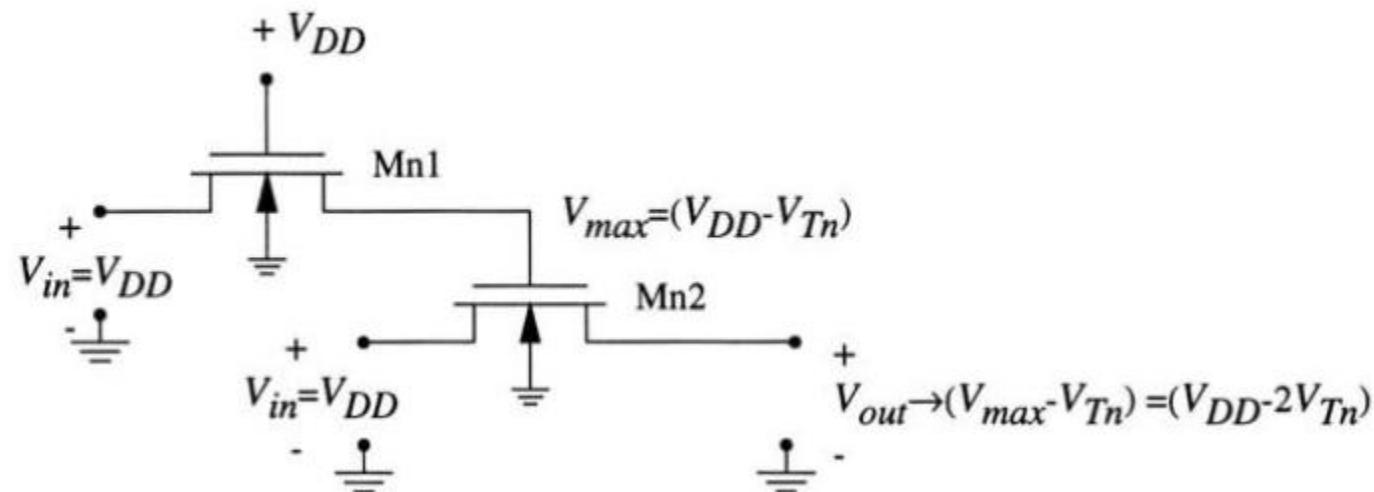
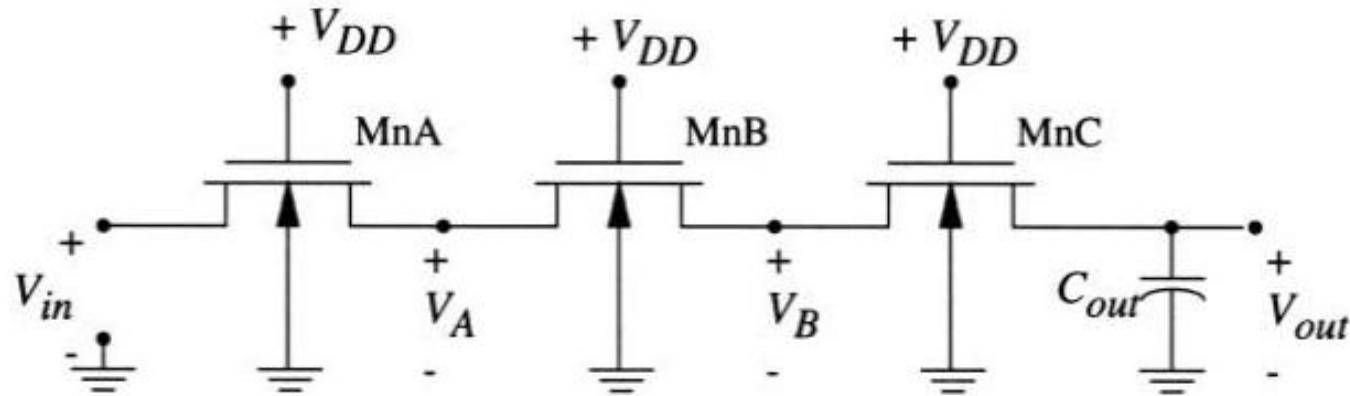
# Reference Books



**"CMOS VLSI Design:A Circuits and Systems Perspective"** 4<sup>th</sup> ed. Addison-Wesley  
**By: Neil H. E. Weste, David Money Harris**

# Pass Transistor and Transmission Gate

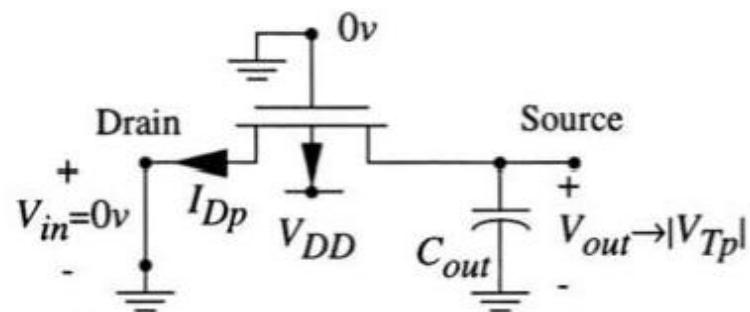
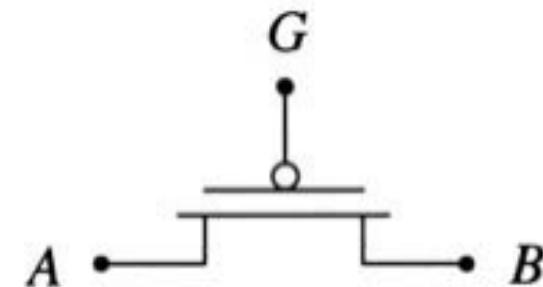
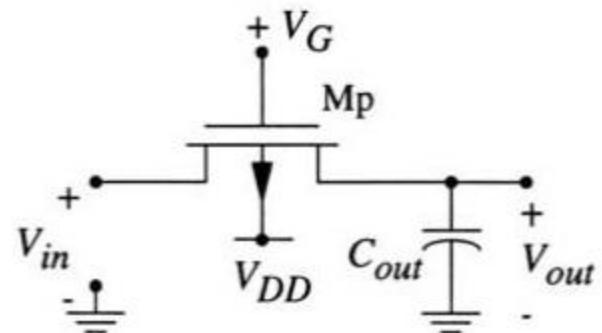
# Pass Transistors (NMOS)



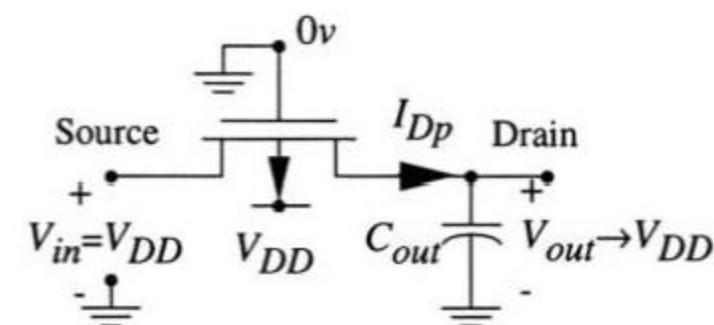
# NMOS

- NMOS Pass transistor passes strong logic 0.
- NMOS Pass transistor passes weak logic 1.

# Pass Transistors (PMOS)

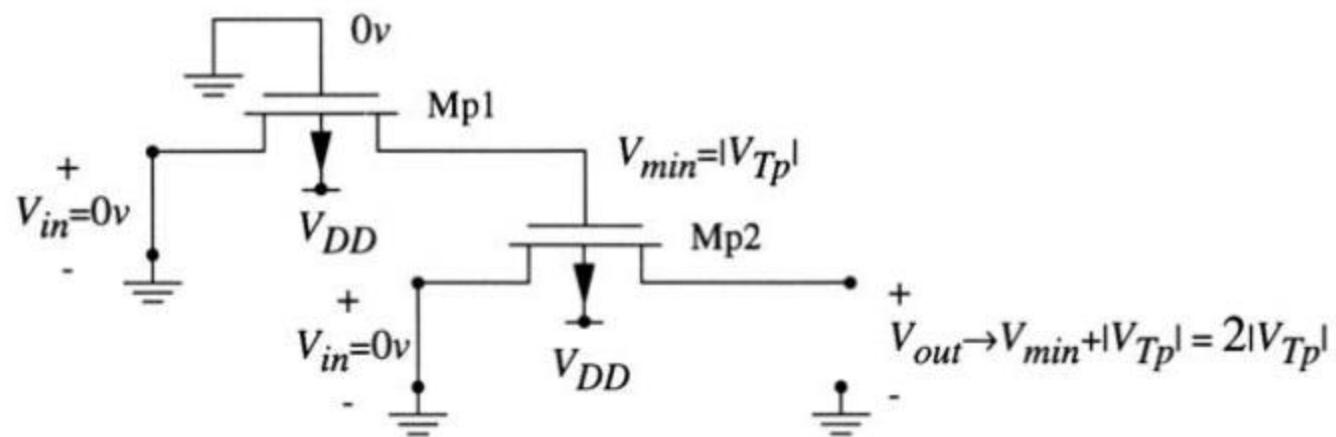
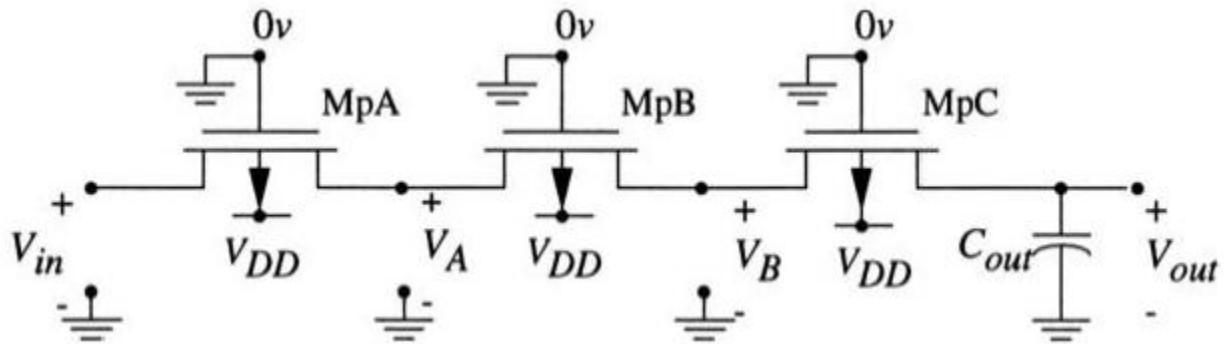


(a) Logic 0 input



(b) Logic 1 input

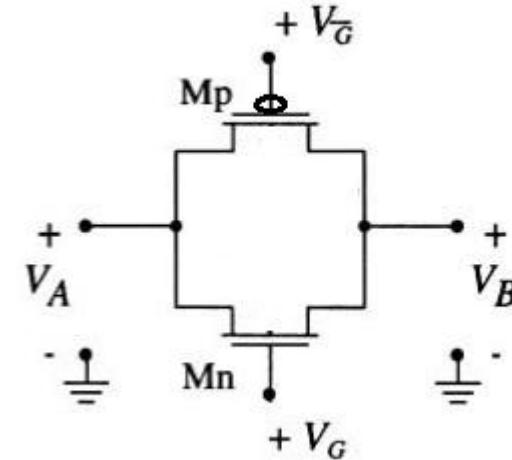
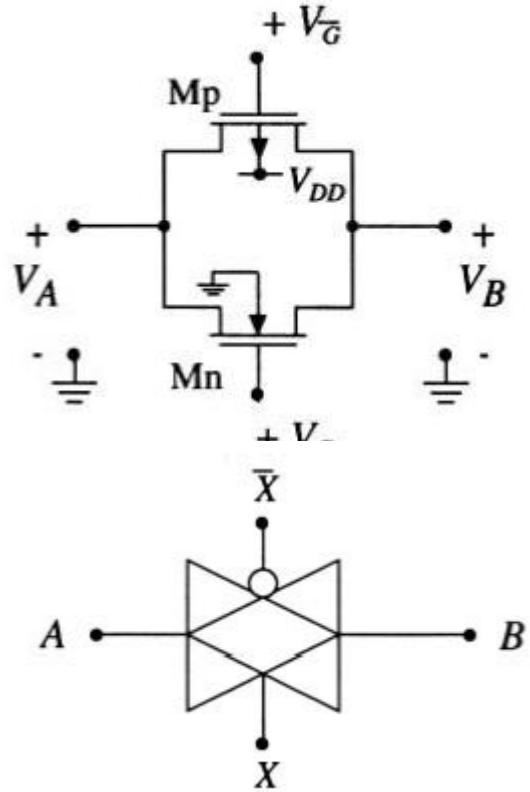
# Pass Transistors (PMOS)



# PMOS

- PMOS Pass transistor passes weak logic 0.
- PMOS Pass transistor passes strong logic 1.

# Transmission Gate

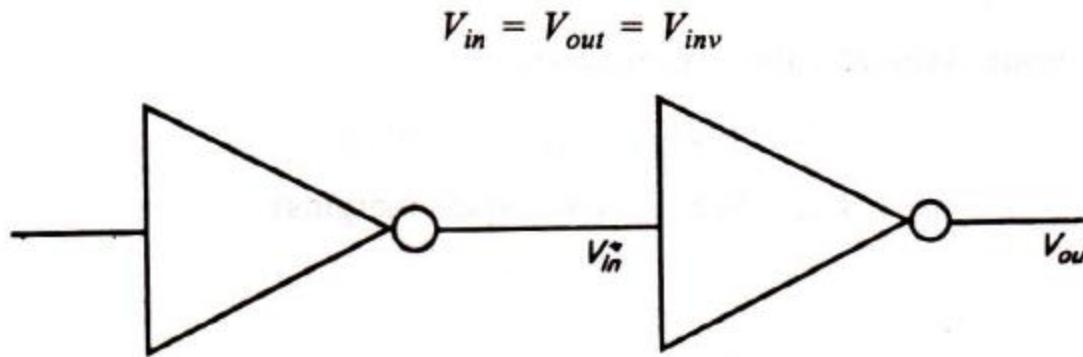


$X$	$A$	$B$
1	0	0
1	1	1
0	0	?
0	1	?

PMOS Pass transistor passes strong logic 1.

NMOS Pass transistor passes strong logic 0.

# Determination of pull-up to pull-down ratio ( $Z_p.U / Z_p.D.$ ) For An Nmos Inverter Driven By Another Nmos Inverter



$$V_{inv} = 0.5V_{DD}$$

$$I_{ds} = K \frac{W}{L} \frac{(V_{gs} - V_t)^2}{2}$$

$$\text{Note} \rightarrow K = \frac{\mu \epsilon_{ins} \epsilon_0}{t_{ox}}$$

In the depletion mode

$$I_{ds} = K \frac{W_{p.u.}}{L_{p.u.}} \frac{(-V_{td})^2}{2} \text{ since } V_{gs} = 0$$

and in the enhancement mode

$$I_{ds} = K \frac{W_{p.d.}}{L_{p.d.}} \frac{(V_{inv} - V_t)^2}{2} \text{ since } V_{gs} = V_{inv}$$

Equating (since currents are the same) we have

$$\frac{W_{p.d.}}{L_{p.d.}} (V_{inv} - V_t)^2 = \frac{W_{p.u.}}{L_{p.u.}} (-V_{td})^2$$

$$Z_{p.d.} = \frac{L_{p.d.}}{W_{p.d.}}; Z_{p.u.} = \frac{L_{p.u.}}{W_{p.u.}}$$

$$\frac{1}{Z_{p.d.}} (V_{inv} - V_t)^2 = \frac{1}{Z_{p.u.}} (-V_{td})^2$$

$$V_{inv} = V_t - \frac{V_{td}}{\sqrt{Z_{p.u.}/Z_{p.d.}}}$$

substitute typical values as follows

$$V_t = 0.2V_{DD}; V_{td} = - 0.6V_{DD}$$

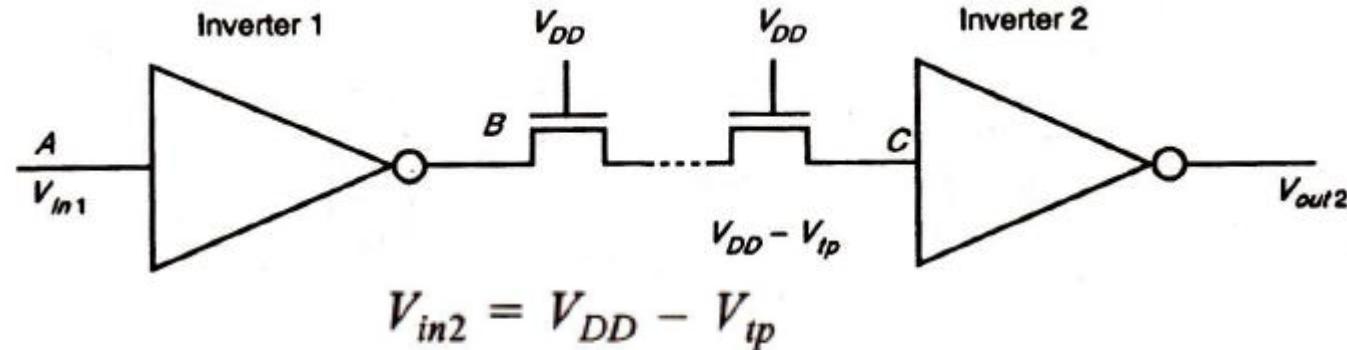
$$V_{inv} = 0.5V_{DD} \text{ (for equal margins)}$$

$$0.5 = 0.2 + \frac{0.6}{\sqrt{Z_{p.u.}/Z_{p.d.}}}$$

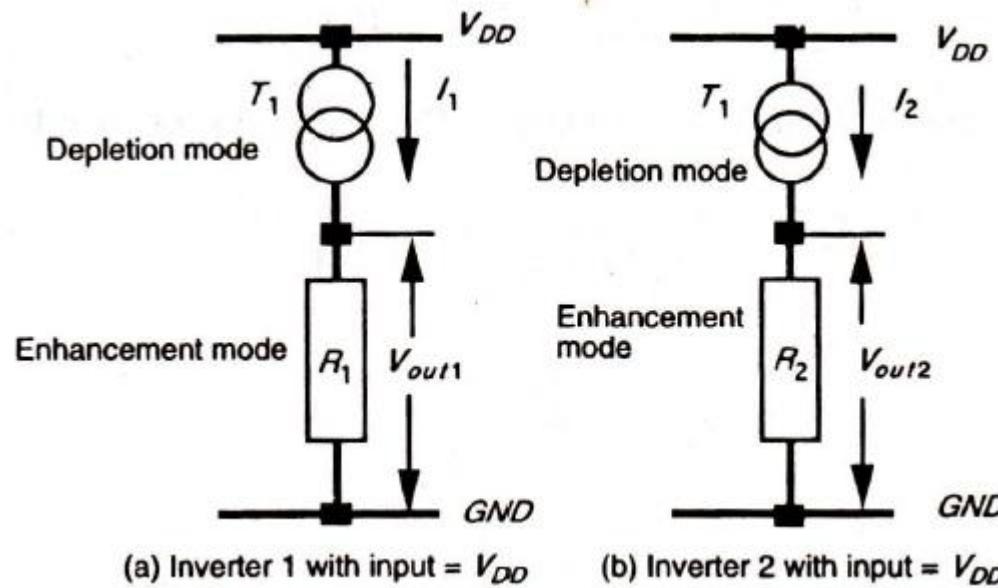
$$\sqrt{Z_{p.u.}/Z_{p.d.}}=2$$

$$Z_{p.u.}/Z_{p.d.} = 4/1$$

Pull-up to pull-down ratio for an Nmos inverter driven through one or more pass transistors



$V_{tp}$  = threshold voltage for a pass transistor



For the p.d. transistor

$$I_{ds} = K \frac{W_{p.d.1}}{L_{p.d.1}} \left( (V_{DD} - V_t) V_{ds1} - \frac{V_{ds1}^2}{2} \right)$$

$$R_1 = \frac{V_{ds1}}{I_{ds}} = \frac{1}{K} \frac{L_{p.d.1}}{W_{p.d.1}} \left( \frac{1}{V_{DD} - V_t - \frac{V_{ds1}}{2}} \right)$$

$$R_1 = \frac{1}{K} Z_{p.d.1} \left( \frac{1}{V_{DD} - V_t} \right)$$

Now, for depletion mode p.u. in saturation with  $V_{GS} = 0$

$$I_1 = I_{ds} = K \frac{W_{p.u.1}}{L_{p.u.1}} \frac{(-V_{sd})^2}{2}$$

$$\text{Note} \rightarrow K = \frac{\mu \epsilon_{ins} \epsilon_0}{t_{ox}}$$

$$I_1 R_1 = V_{out\ 1}$$

$$V_{out1} = I_1 R_1 = \frac{Z_{p.d.1}}{Z_{p.u.1}} \left( \frac{1}{V_{DD} - V_t} \right) \frac{(V_{td})^2}{2}$$

Consider inverter 2 (Figure 2.10(b)) when input =  $VDD - V_{tp}$ .

$$R_2 = \frac{1}{K} Z_{p.d.2} \frac{1}{((V_{DD} - V_{tp}) - V_t)}$$

$$I_2 = K \frac{1}{Z_{p.u.2}} \frac{(-V_{td})^2}{2}$$

Taking typical values

$$V_t = 0.2V_{DD}$$

$$V_{tp} = 0.3V_{DD}^*$$

$$\frac{Z_{p.u.2}}{Z_{p.d.2}} = \frac{Z_{p.u.1}}{Z_{p.d.1}} \frac{0.8}{0.5}$$

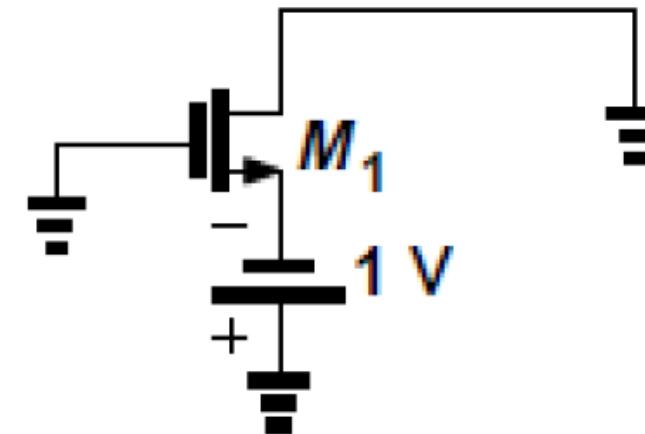
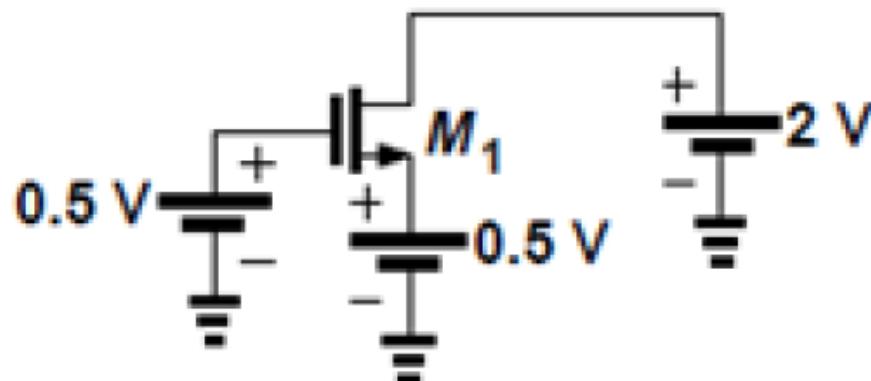
$$\frac{Z_{p.u.2}}{Z_{p.d.2}} \doteq 2 \quad \frac{Z_{p.u.1}}{Z_{p.d.1}} = \frac{8}{1}$$

# 2016 End Sem

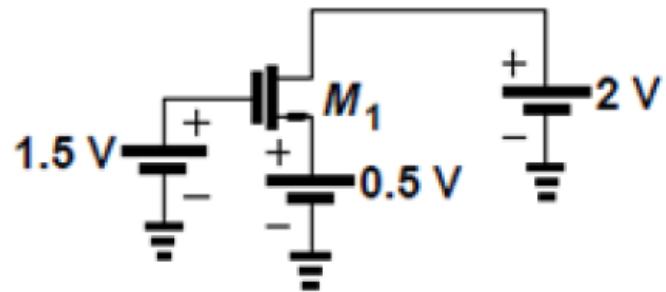
Compare BJT and MOSFET with respect to following parameters:

- (i) Transconductance value
- (ii) Input impedance
- (iii) Noise
- (iv) Current handling capability

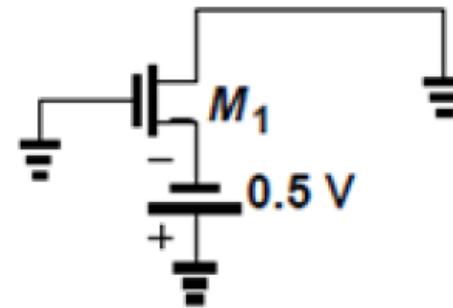
Find the region of operation for NMOS based circuits given in FIG. 3C.  
Assume  $V_T = 0.4V$



Find the region of operation for the circuit given in FIG. Q 2C (i) and (ii).  
Threshold voltage  $V_{TH} = 0.4$  V.



(i)



(ii)

FIG. Q 2C

# BiCMOS Inverter

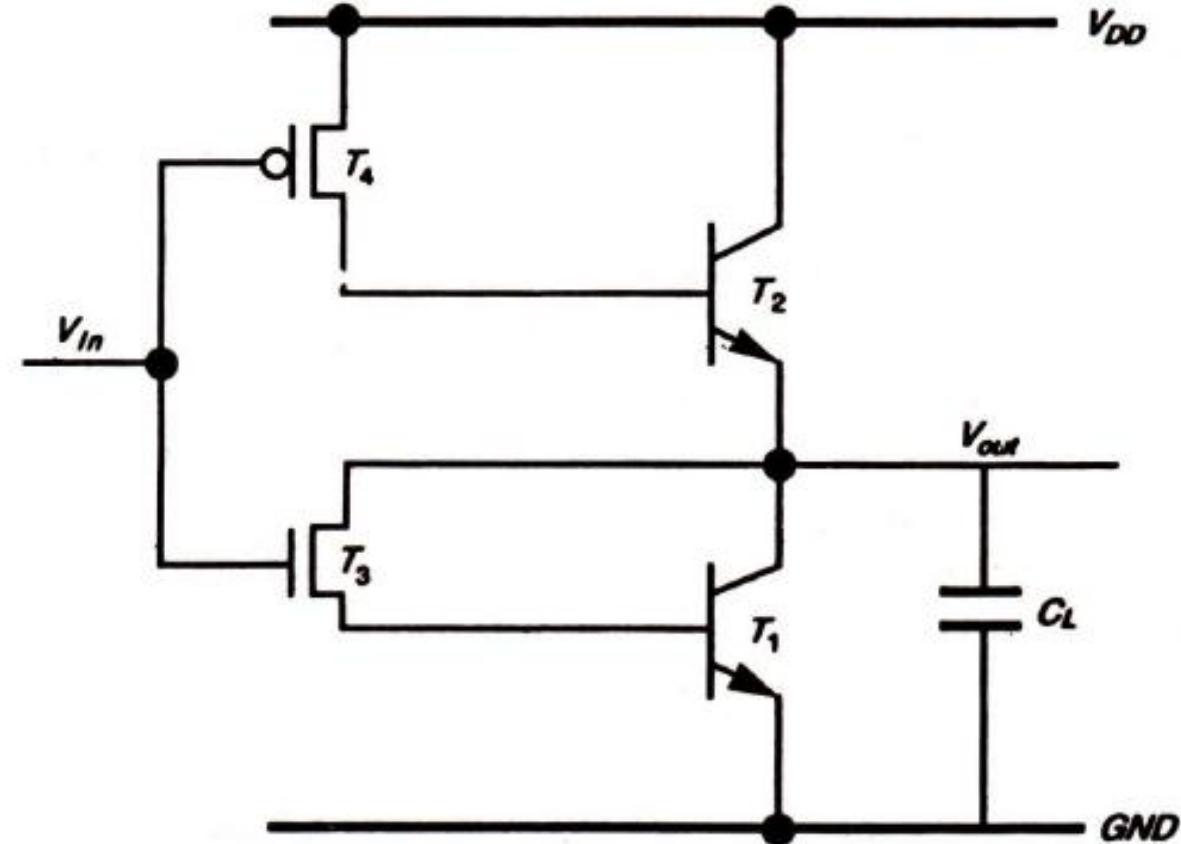
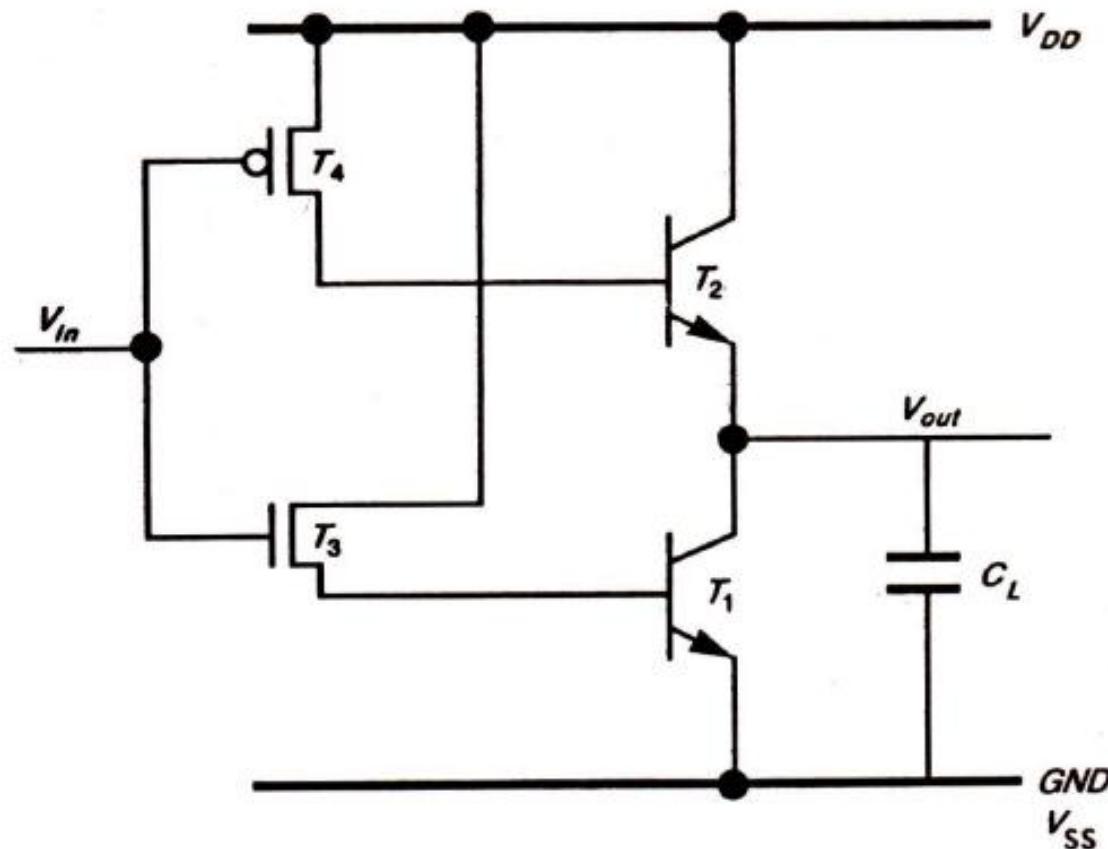
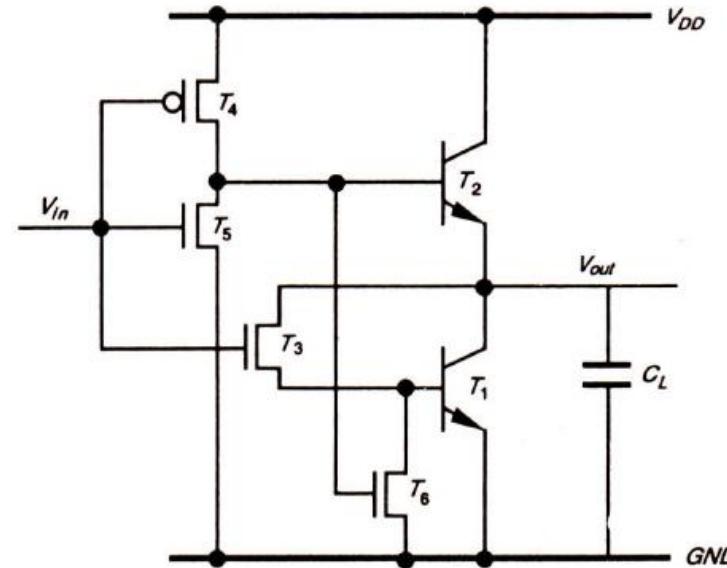
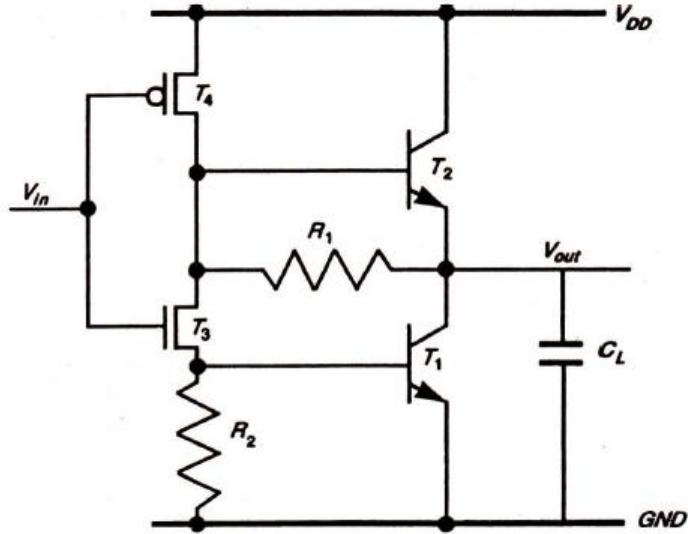


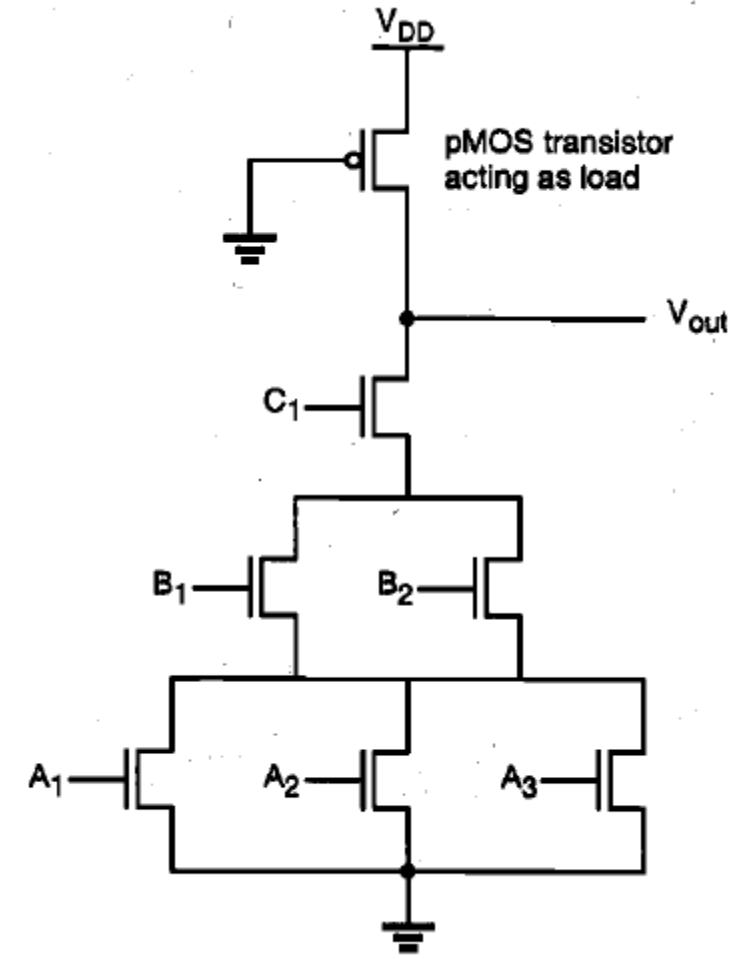
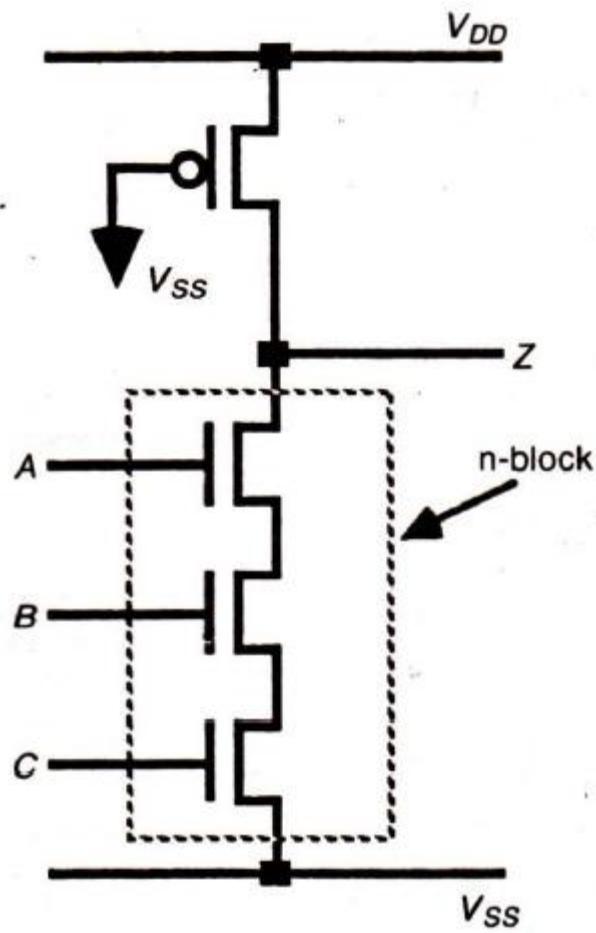
FIGURE 2.17 A simple BiCMOS inverter.

# BiCMOS Inverter

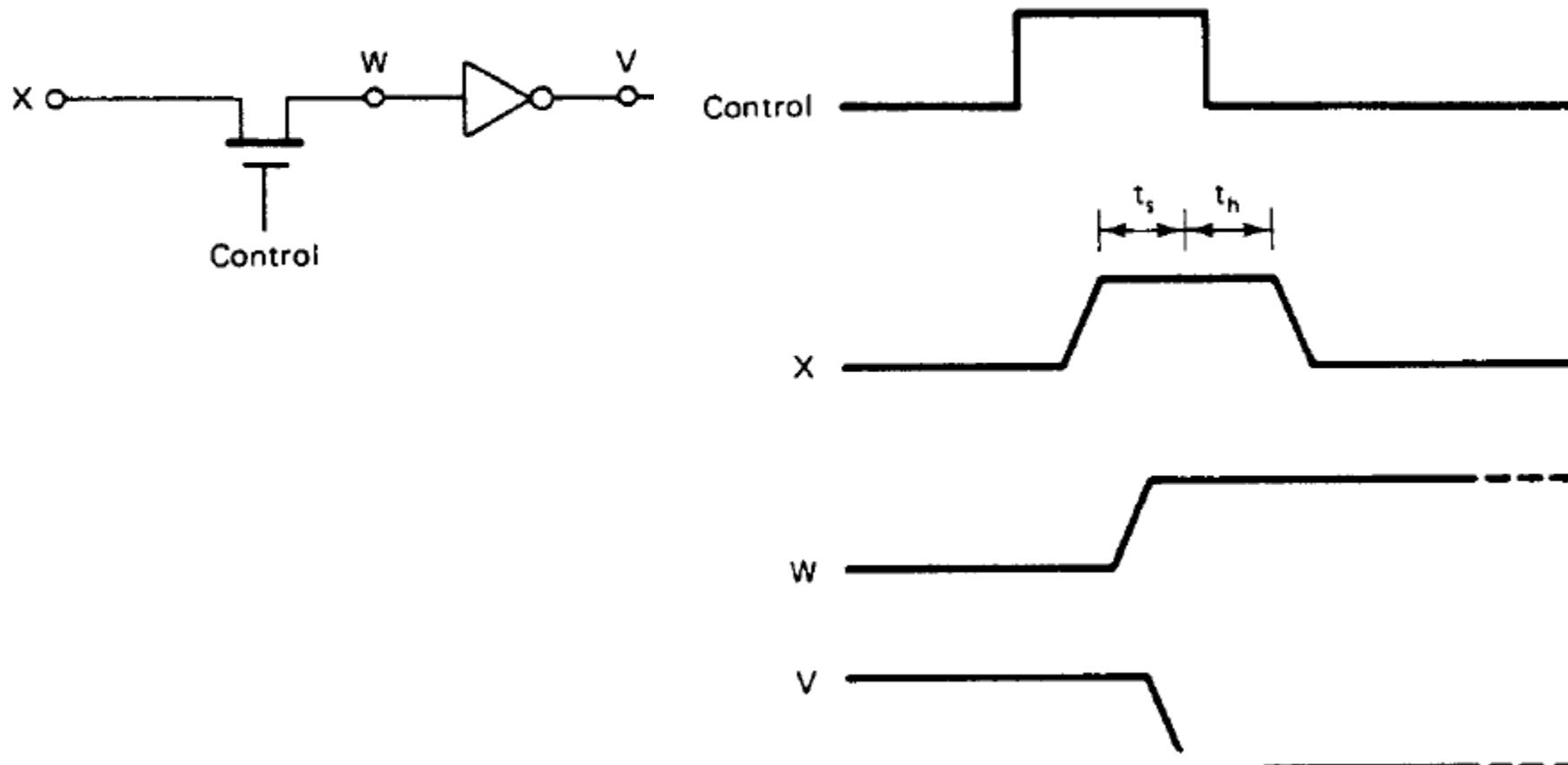


RE 2.19 An improved BiCMOS inverter with better output logic levels.

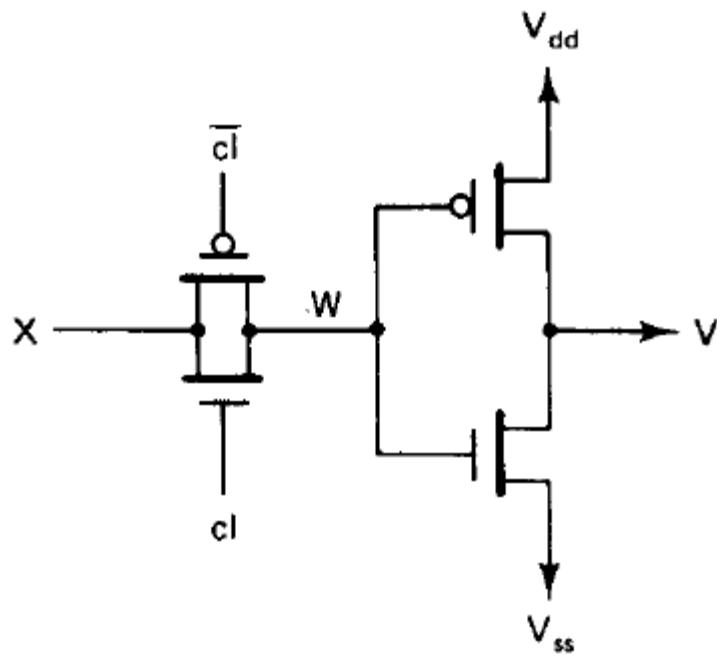
# Pseudo NMOS Logic



# NMOS Dynamic latch



# CMOS dynamic latch

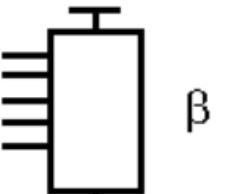


# Dynamic Logic

# Static logic

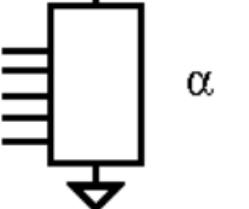
To build a logic gate  $\bar{f}(x_1, \dots, x_n)$ , need to build two switch networks:

The pullup network connects the output to Vdd when  $f$  is false.



$\beta$  pMOS only, since only passes 1

The pulldown network connects the output to Gnd when  $f$  is true.



$\alpha$  nMOS only, since only passes 0

Pulldown

$$\alpha(x_1, \dots, x_n) = f(x_1, \dots, x_n)$$

Pullup

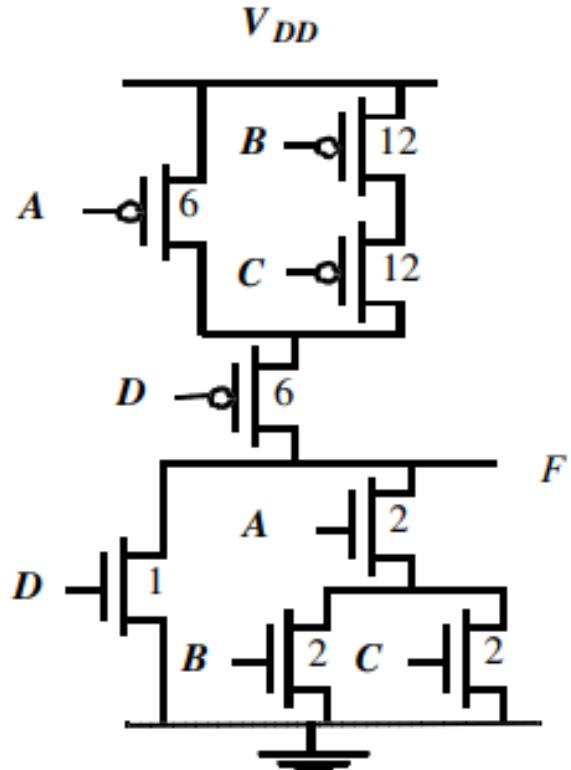
$$\beta(\bar{x}_1, \dots, \bar{x}_n) = \bar{f}(x_1, \dots, x_n) \quad (\text{since pMOS invert inputs})$$

# Static CMOS logic

1. **High noise margins** :  $V_{OH}$  and  $V_{OL}$  are at  $V_{DD}$  and GND, respectively.
2. **No static power consumption** : There never exists a direct path between  $V_{DD}$  and  $V_{SS}$  (GND) in steady-state mode.
3. **Comparable rise and fall times**: (under the appropriate scaling conditions)

# Static CMOS Sizing

- for symmetrical response (dc, ac)
- for performance



**Input Dependent**  
**Focus on worst-case**

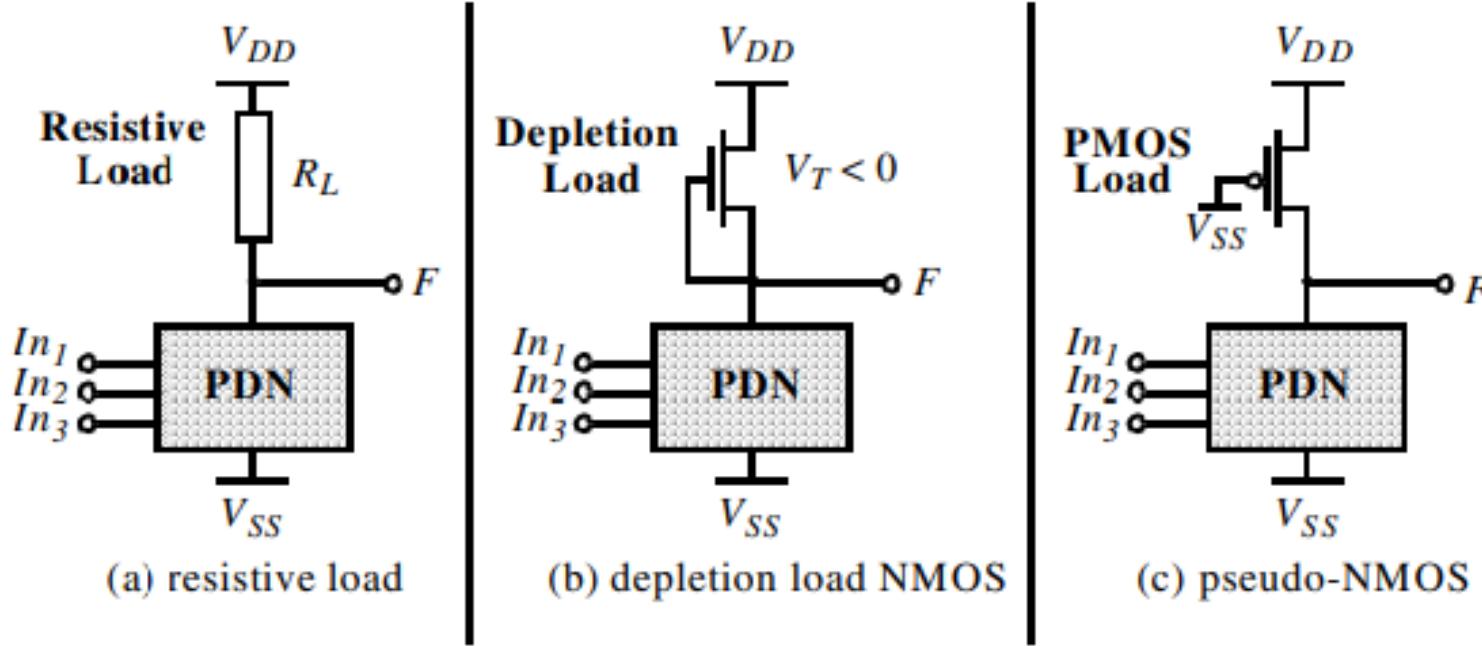
- assume  $\mu_n=3 \times \mu_p$  (i.e. n-channel transistors has 3 times the transconductance as that of p-channel.)

**Comparing with equivalent Inverter**

Problem: Area, as number of transistor are doubled.

Too many series transistors can effect switching speed.

# Ratioed logic



**Goal: to reduce the number of devices over complementary CMOS**

PMOS size  
0.25 of NMOS

# Psuedo-NMOS

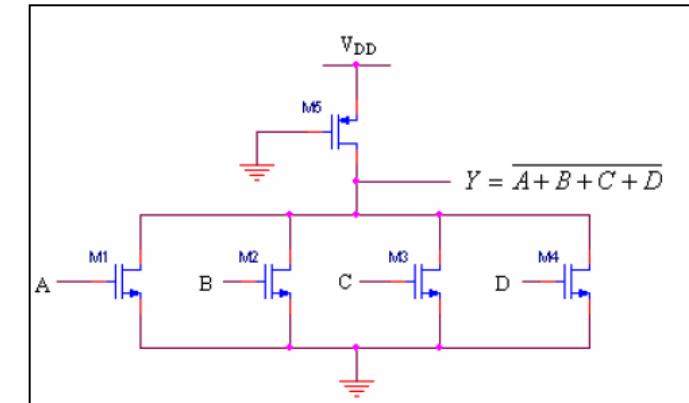
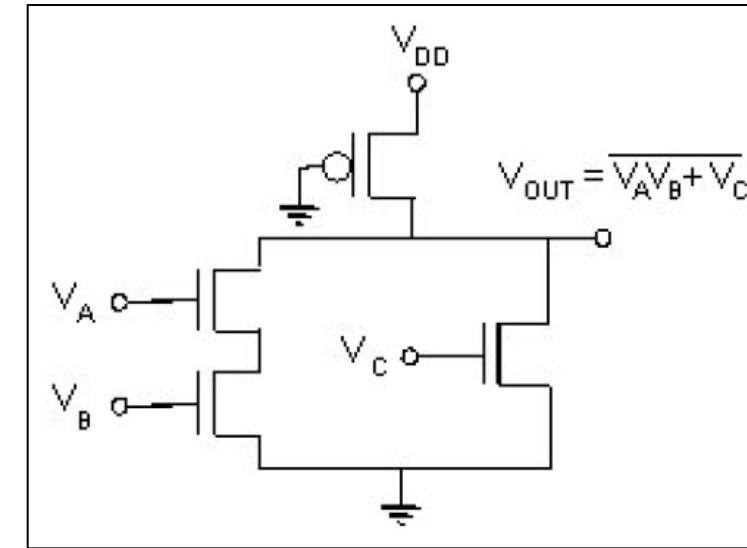
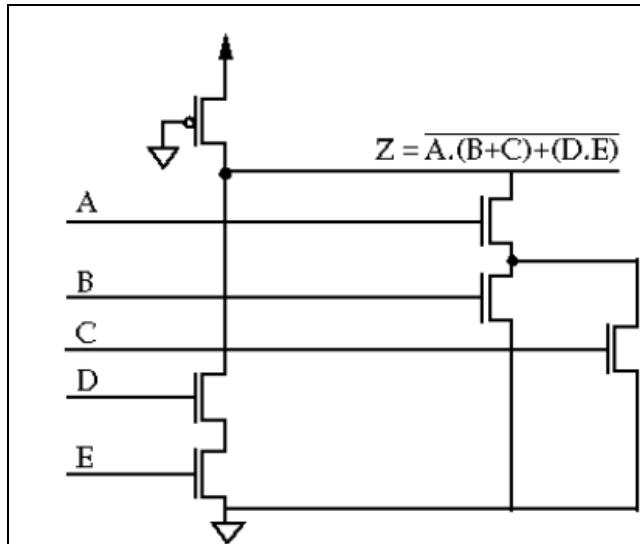
Implement:

2-input NAND Logic

$$V_{OUT} = \overline{V_A V_B + V_C}$$

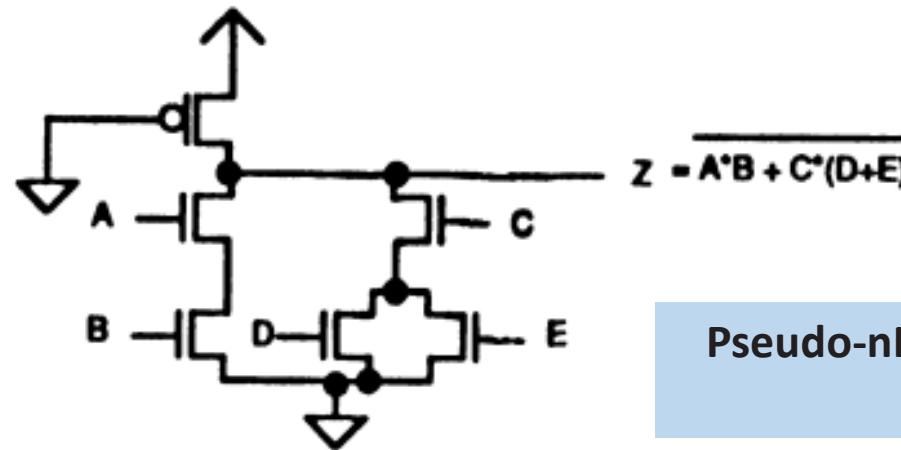
$$Y = \overline{A + B + C + D}$$

$$Z = \overline{A.(B+C)+(D.E)}$$



# Psuedo-NMOS

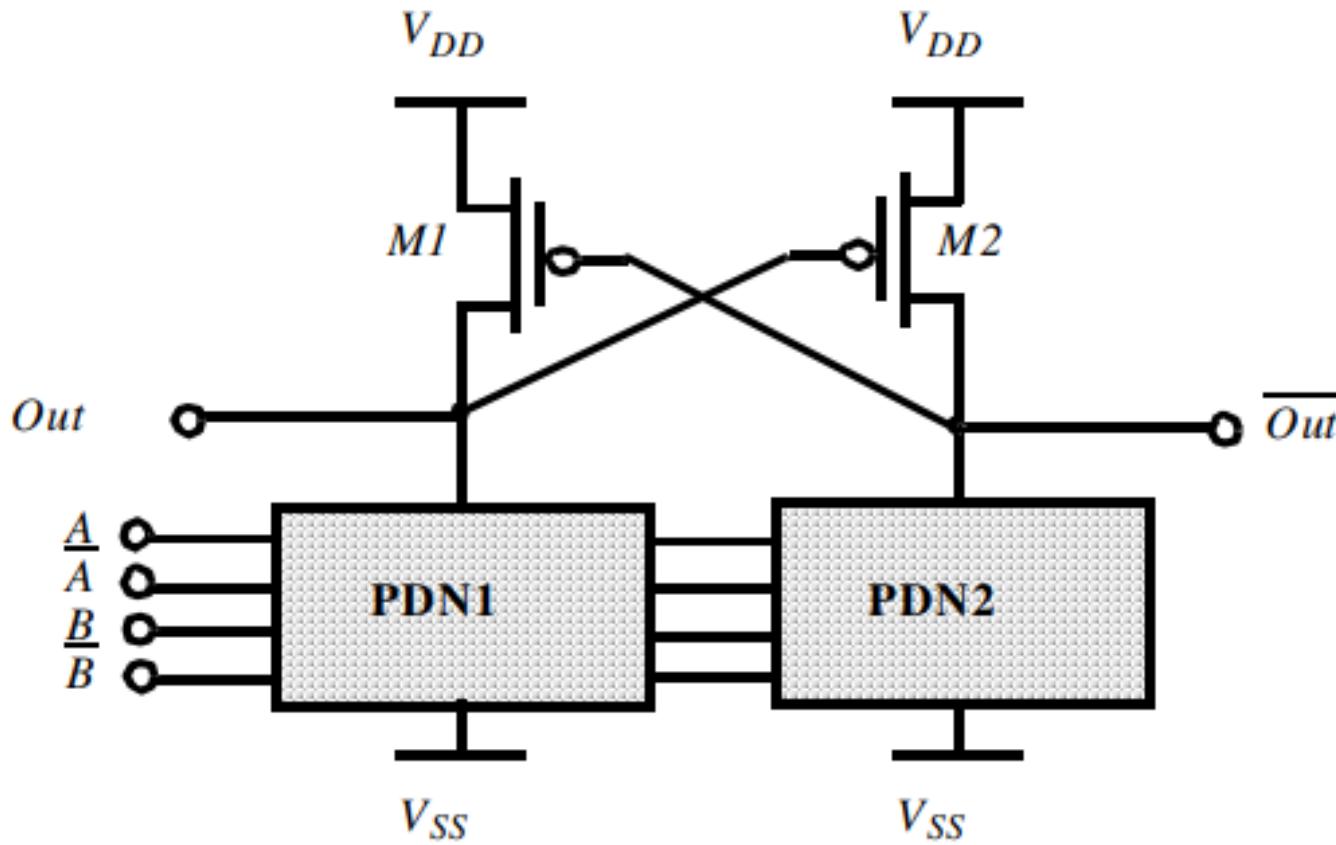
- ◆ *Disadvantages of previous circuit :*
  - Almost twice as many transistors as equivalent NMOS implementation.
  - If there are too many series transistors in the tree, switching speed is reduced.
- ◆ Try a pseudo NMOS circuit:-



Pseudo-nMOS worked well for wide NOR structures

- ◆ The pull-up p-channel transistor is always conducting.
  - *Disadvantages:* high d.c. dissipation & slow rise time.

# Dual Cascode Voltage Switch Logic (DCVSL)



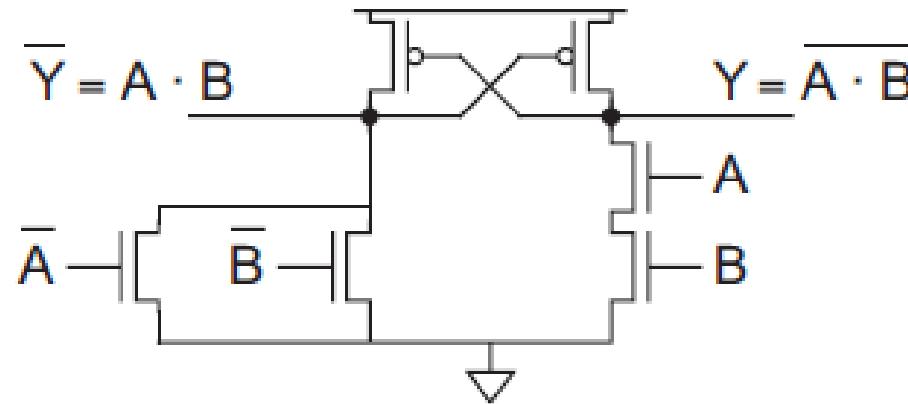
**Dual Cascode Voltage Switch Logic (DCVSL)**

# Dual Cascode Voltage Switch Logic (DCVSL)

- ❖ Comprises benefits of ratioed circuits without the static power consumption.
- ❖ It uses both true and complementary input signals and computes both true and complementary outputs using a pair of nMOS pulldown networks.
- ❖ For any given input pattern, one of the pulldown networks will be ON and the other OFF.
- ❖ CVSL has a potential **speed advantage** because all of the logic is performed with nMOS transistors

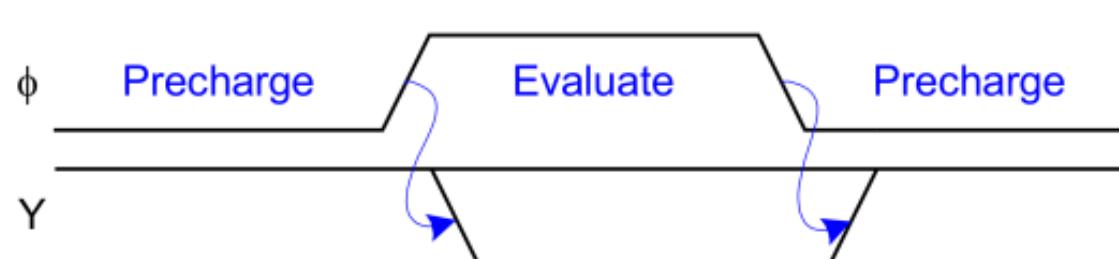
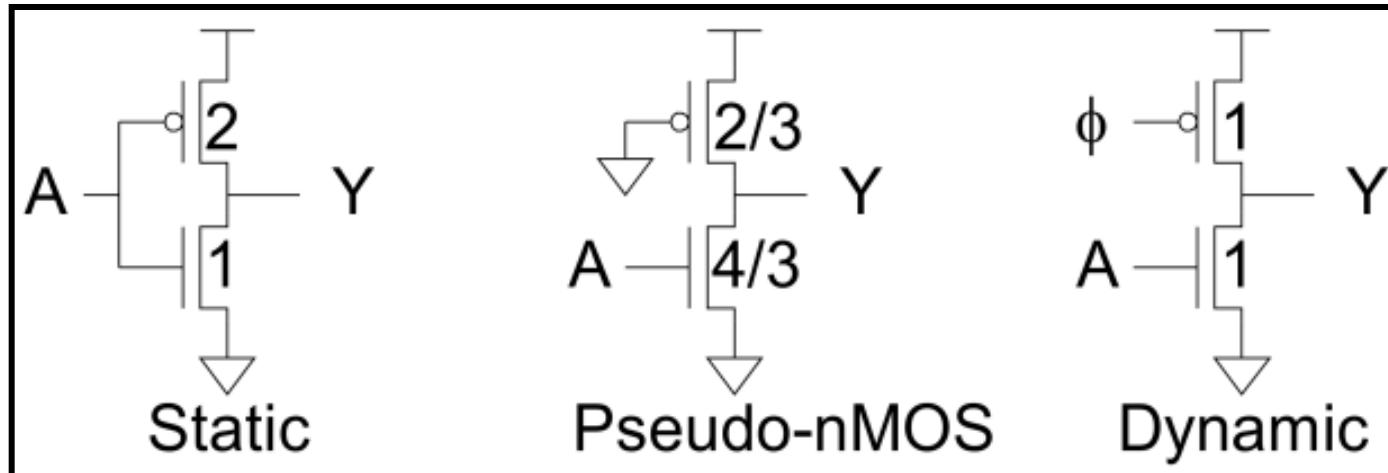
# Dual Cascode Voltage Switch Logic (DCVSL)

Implement AND-NAND gate using DCVSL



# Dynamic Logic

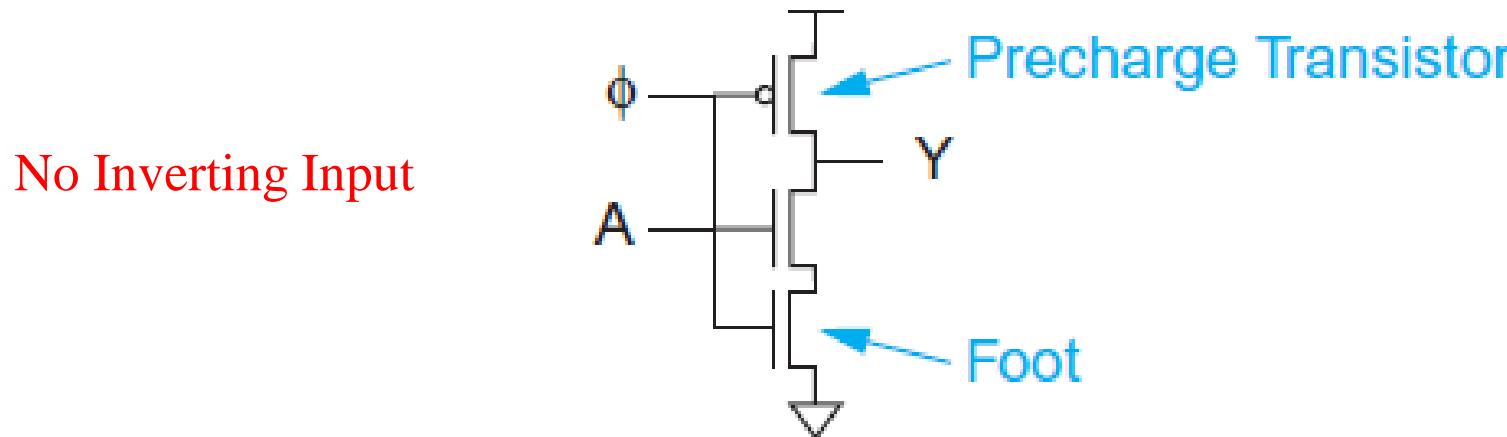
- ❖ Dynamic gates use a clocked pMOS pullup
- ❖ Two modes of operation: precharge and evaluate



What if input A is 1  
during precharge?

# Dynamic Logic

- ❖ When the input cannot be guaranteed to be 0 during precharge, an **extra clocked evaluation transistor** can be added to the bottom of the nMOS stack to avoid contention.



This circuit is dynamic because during evaluation, the output high level at  $Y$  is maintained by the stray capacitance at the output node. If  $\phi$  stays high (i.e. evaluation period) for a long time,  $Y$  may eventually discharge to a low logic level.

# Dynamic Logic - Monotonicity

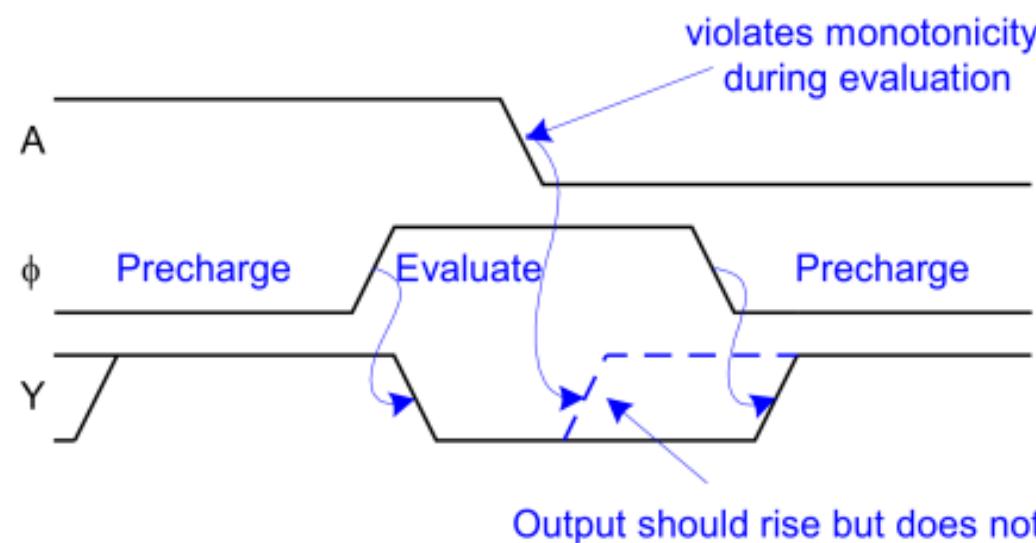
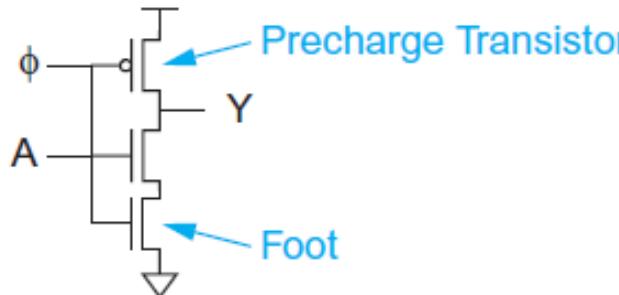
Dynamic gates require monotonically rising inputs during evaluation:

$$0 \rightarrow 0$$

$$0 \rightarrow 1$$

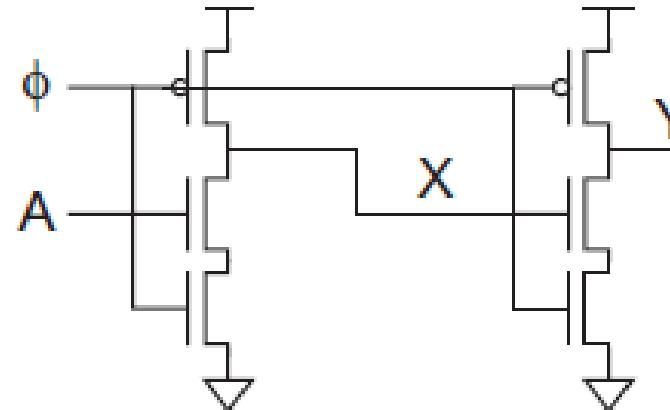
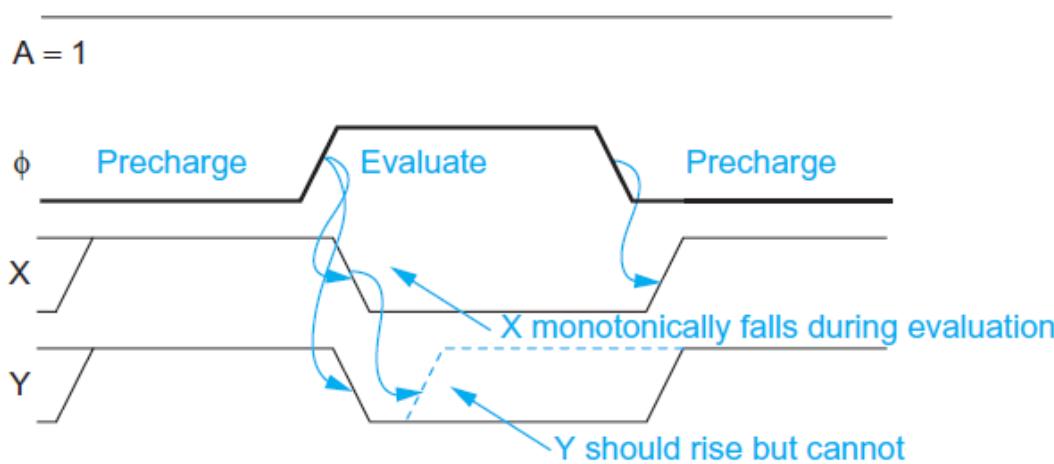
$$1 \rightarrow 1$$

But not  $1 \rightarrow 0$



# Dynamic Logic - Monotonicity

Even  $1 \rightarrow 1$  also creates problems  
in series Gates:



Dynamic gates sharing the same clock cannot be directly connected.

This problem is often overcome with domino logic

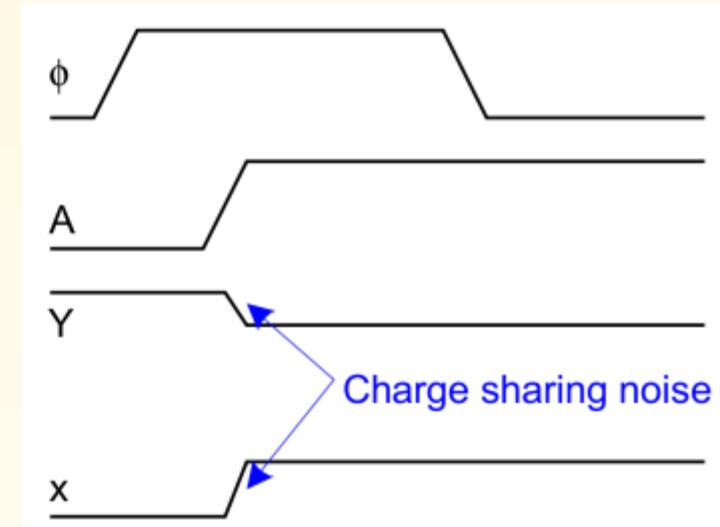
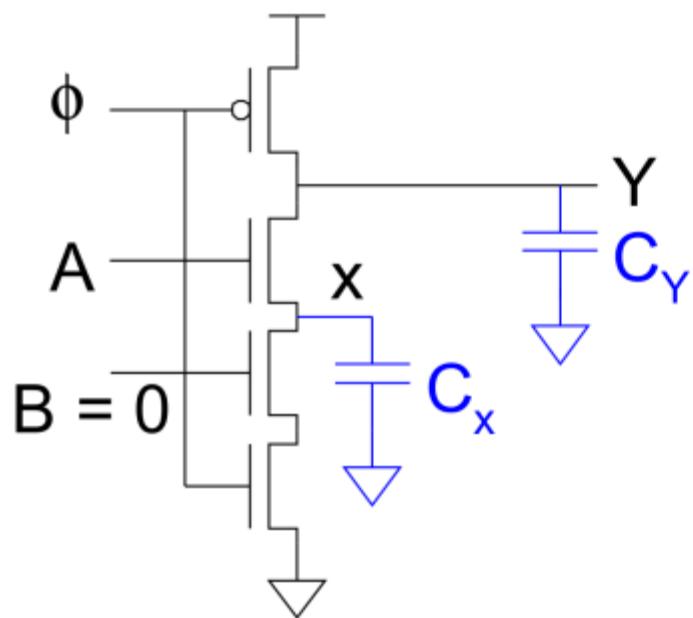
# Cascading Problem in Dynamic CMOS Logic

- If several stages of the previous CMOS dynamic logic circuit are cascaded together using the same clock  $\phi$ , a problem in evaluation involving a built-in “race condition” will exist
- Consider the two-stage dynamic logic circuit below:
  - During **pre-charge**, both  $V_{out1}$  and  $V_{out2}$  are pre-charged to  $V_{dd}$
  - When  $\phi$  goes high to begin **evaluation**, all inputs at stage 1 require some finite time to resolve, but during this time, the charge may erroneously be discharged from  $V_{out2}$ 
    - e.g. assume that eventually the 1<sup>st</sup> stage NMOS logic tree conducts and fully discharges  $V_{out1}$ , but since all the inputs to the N-tree are not immediately resolved, it takes some time for the N-tree to discharge  $V_{out1}$  to GND finally.
    - If, during this time delay, the 2<sup>nd</sup> stage has the input condition shown with the bottom NMOS transistor gate at logic 1, then  $V_{out2}$  will start to fall and discharge its load capacitance until  $V_{out1}$  finally evaluates and turns off the top series NMOS transistor in stage 2
  - The result is an error in the output of the 2<sup>nd</sup> stage  $V_{out2}$

# Dynamic Logic

## Charge Sharing

- Dynamic gates suffer from charge sharing

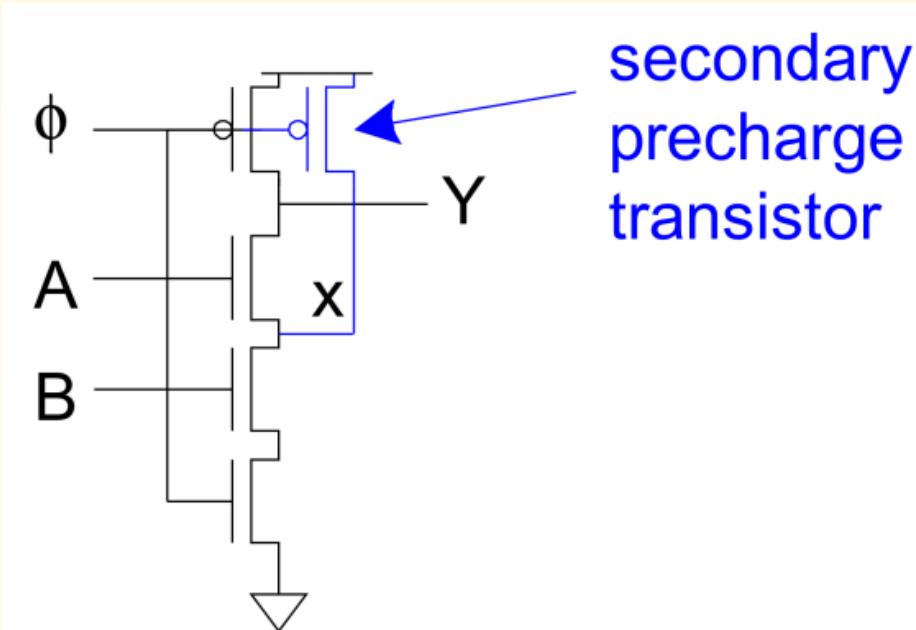


$$V_x = V_y = \frac{C_y}{C_x + C_y} V_{DD}$$

# Dynamic Logic

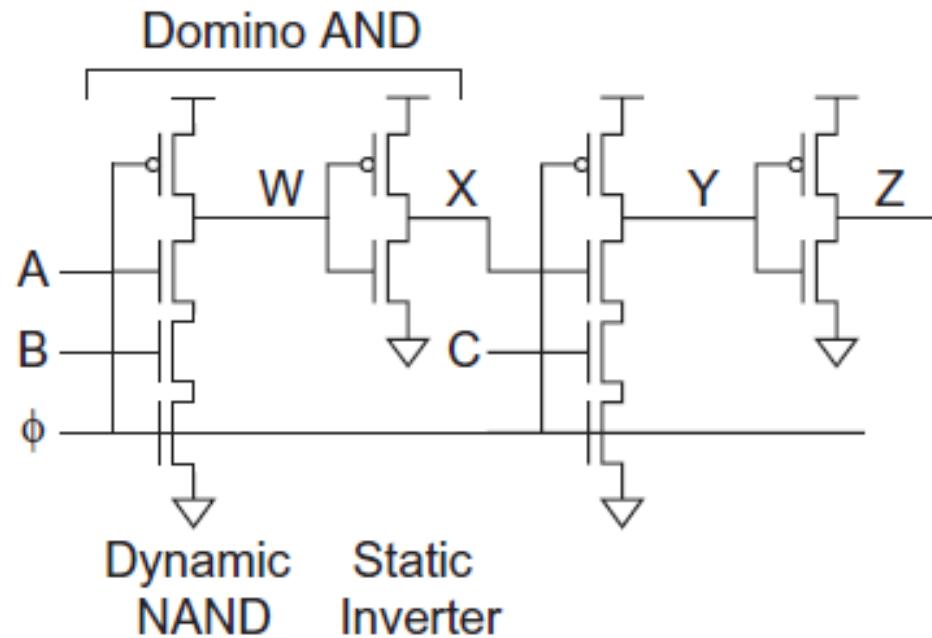
## Secondary Precharge

- Solution: add secondary precharge transistors
  - Typically need to precharge every other node
- Big load capacitance on Y helps as well

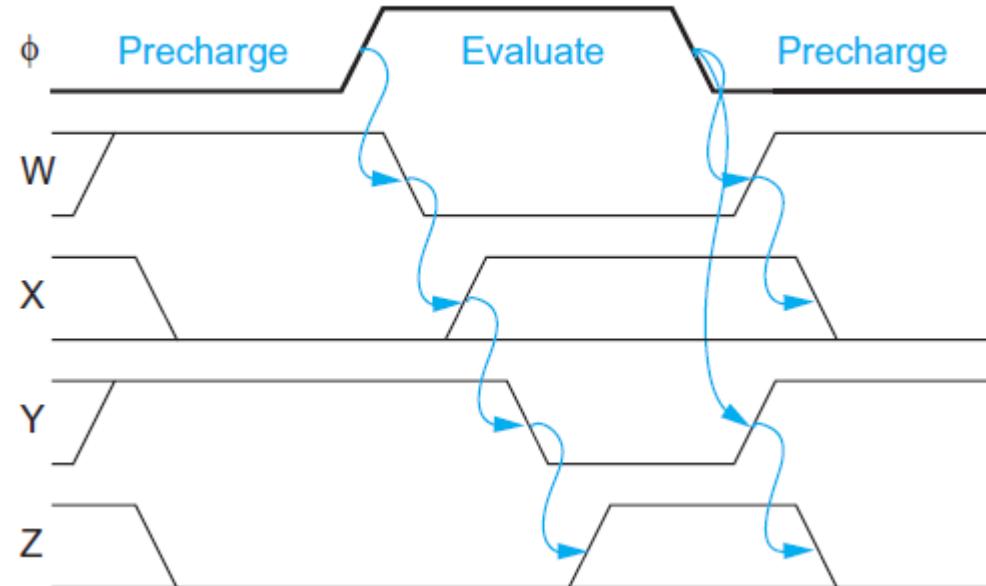
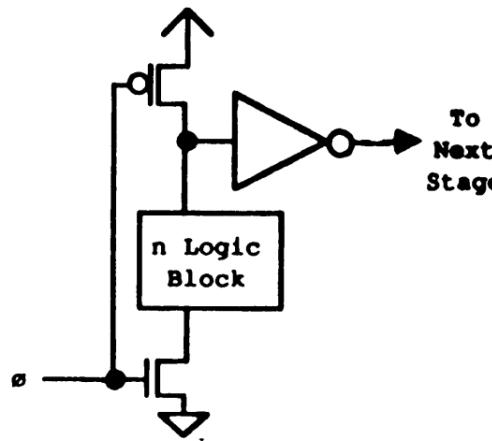
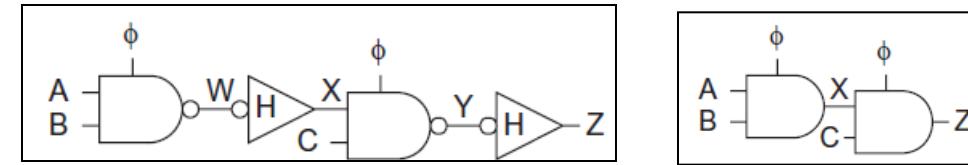
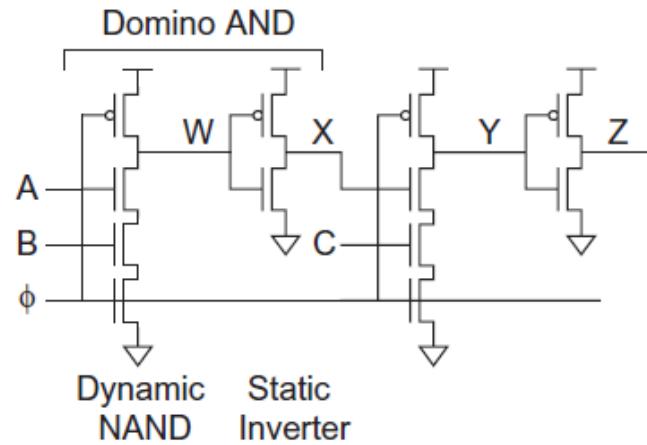


# Dynamic Logic - Domino

- ❖ Follow dynamic stage with inverting static gate.
- ❖ Dynamic/static pair is called domino gate Produces monotonic outputs.



# Dynamic Logic - Domino



Precharge occurs in parallel, but evaluation occurs sequentially

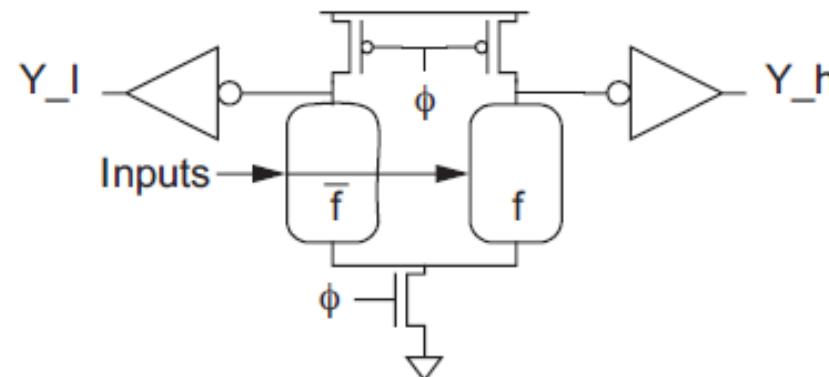
# Dynamic Logic - Domino

## Disadvantages of domino logic:-

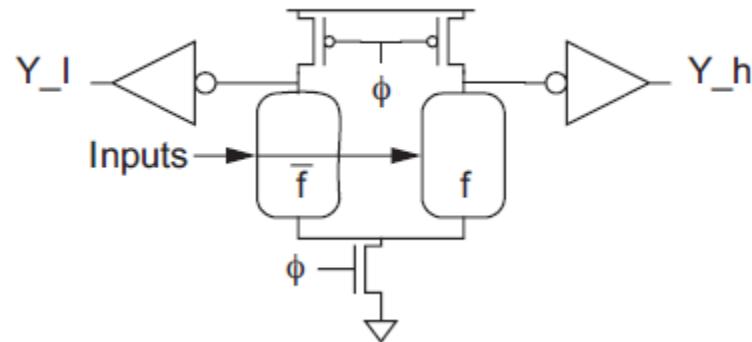
- ❖ Only **non-inverting logic is possible**, i.e. AND, OR but not NAND, NOR, or XOR.
- ❖ Each gate **needs an inverter**; hence more transistors.
- ❖ Suffer from charge sharing effect (considered later)

## Dual-rail domino solves this problem

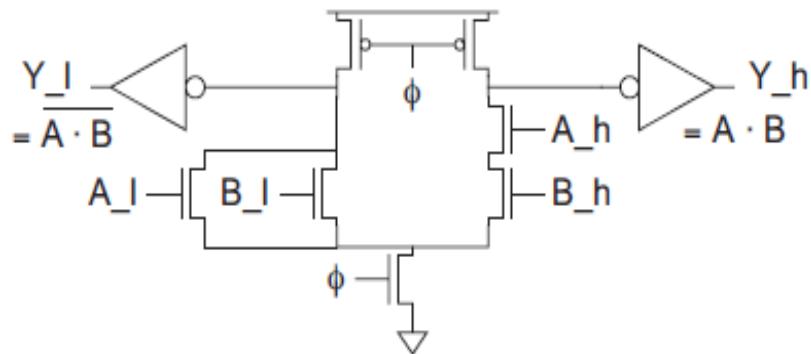
- ❖ Takes true and complementary inputs.
- ❖ Produces true and complementary outputs



# Dynamic Logic – Dual rail Domino



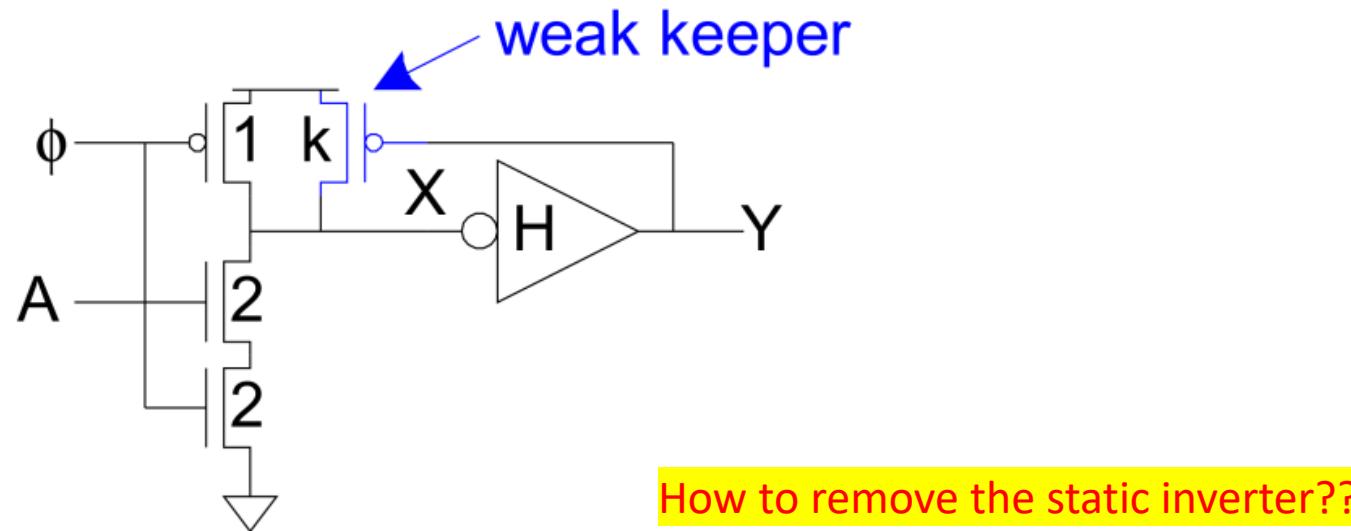
<i>sig_h</i>	<i>sig_I</i>	Meaning
0	0	Precharged
0	1	'0'
1	0	'1'
1	1	Invalid



AND/NAND Logic

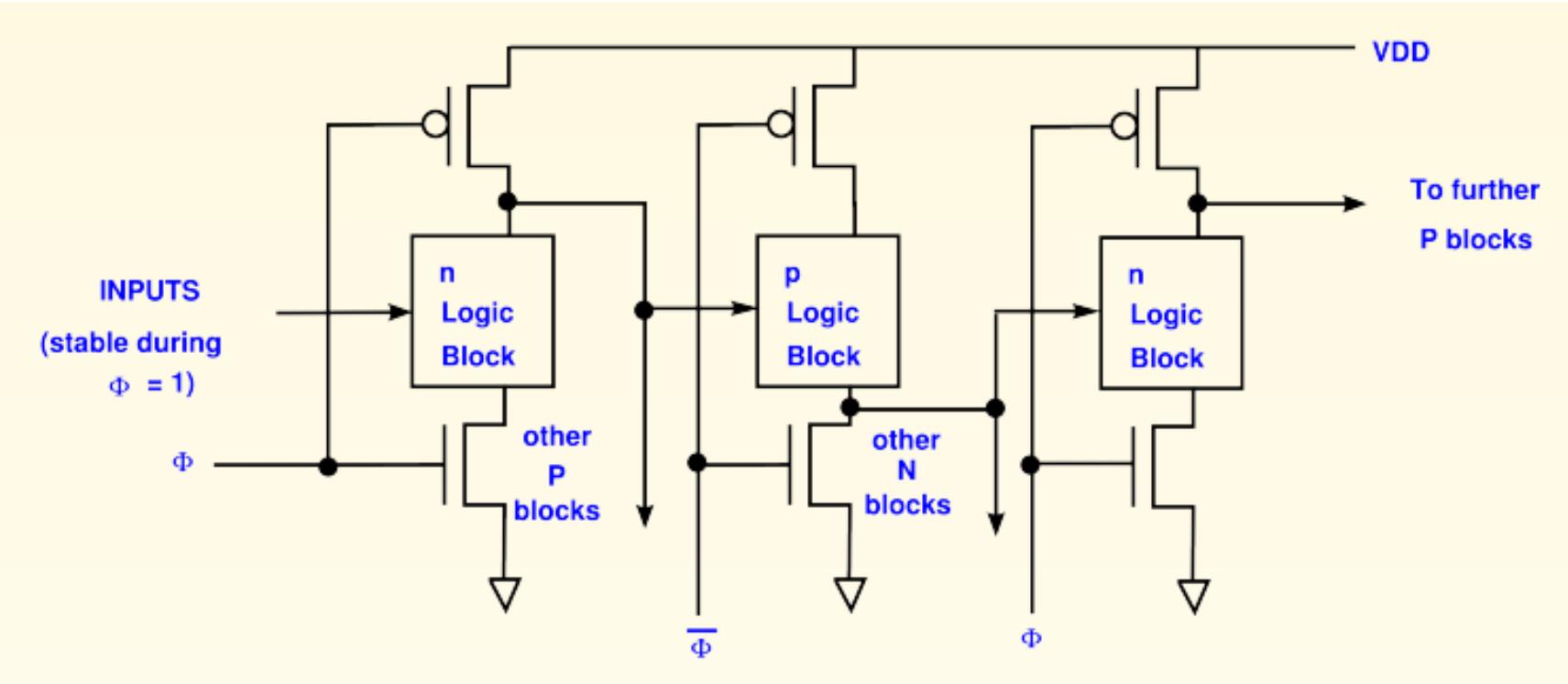
# Domino Logic

- Dynamic node floats high during evaluation
  - Transistors are leaky ( $I_{off} \neq 0$ )
  - Dynamic value will leak away over time
  - Formerly milliseconds, now nanoseconds!
- Use keeper to hold dynamic node
  - Must be weak enough not to fight evaluation
- Leakage Power!



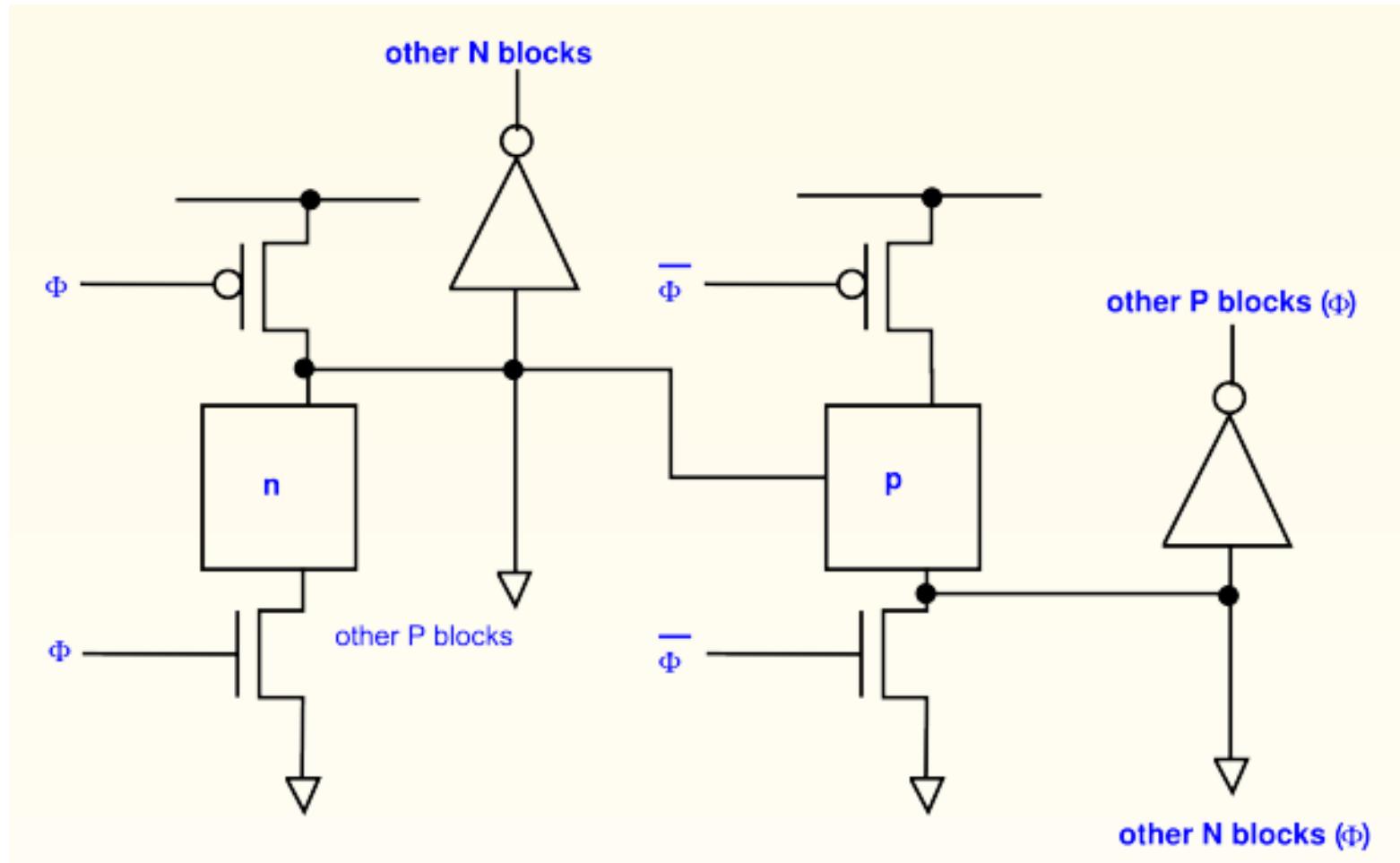
# Domino Logic

N-P Domino



# Domino Logic

N-P Domino

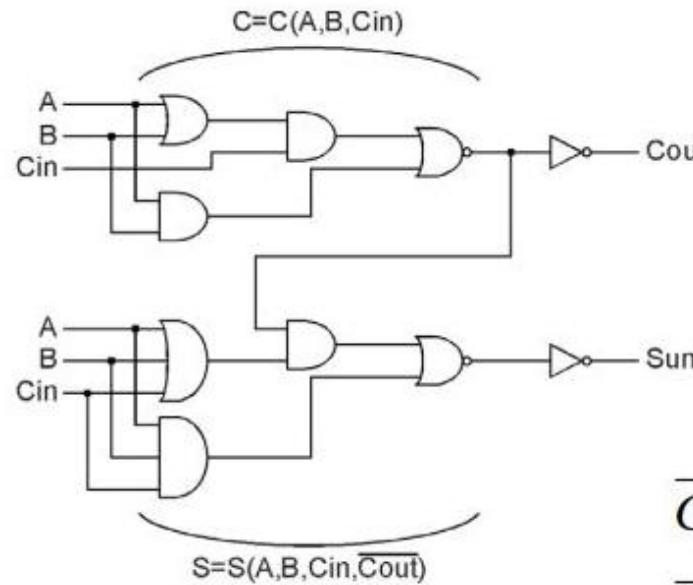


# Domino Logic - Summary

- Domino logic is attractive for high-speed circuits
  - 1.5-2x faster than static CMOS
- Many Challenges
  - Monotonicity
  - Leakage
  - Charge sharing
  - Noise
- Used in previous generation high-performance microprocessors and in some recent embedded processors

# Example

## Implement a Full Adder Using Domino Logic

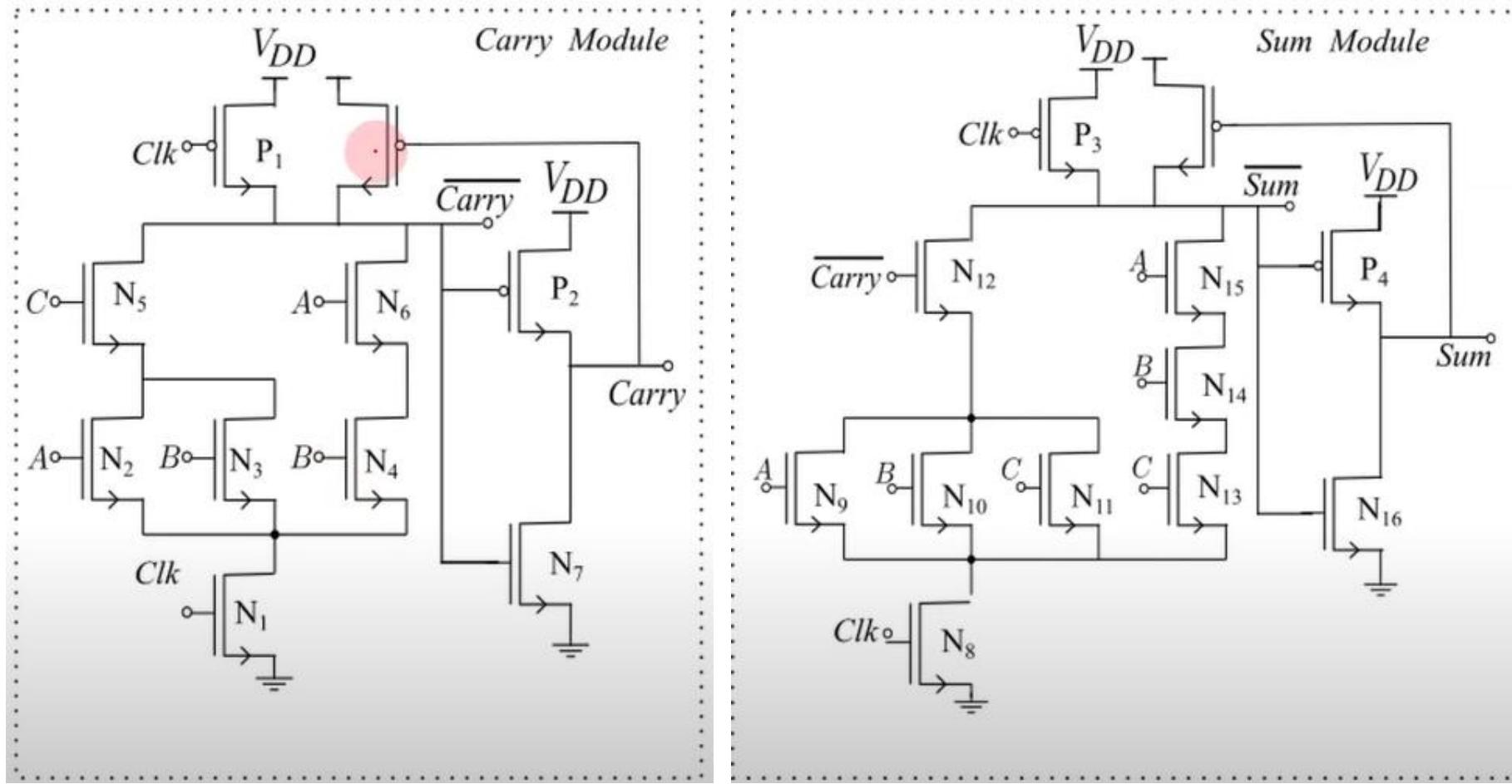


**Full Adder**

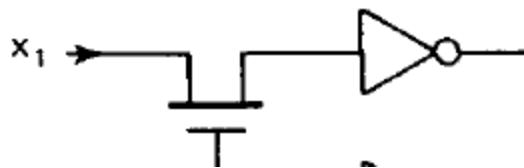
$$\overline{C_{out}} = \overline{AB} + C_{in}(A + B)$$
$$\overline{S} = \overline{\overline{C_{out}}(A + B + C_{in}) + ABC_{in}}$$

Signal from circuit for  $\overline{C_{out}}$  can  
be re-used for S ( $\rightarrow$  two stages)

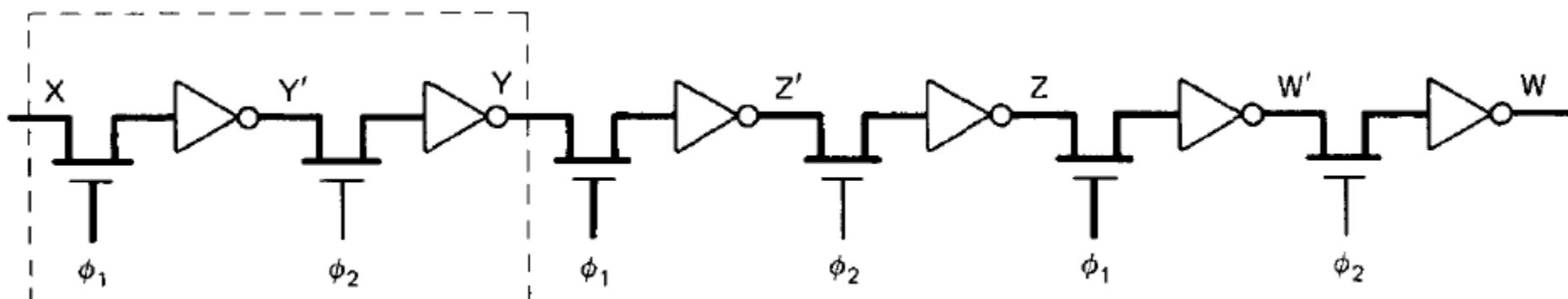
# Example



# Dynamic Shift register

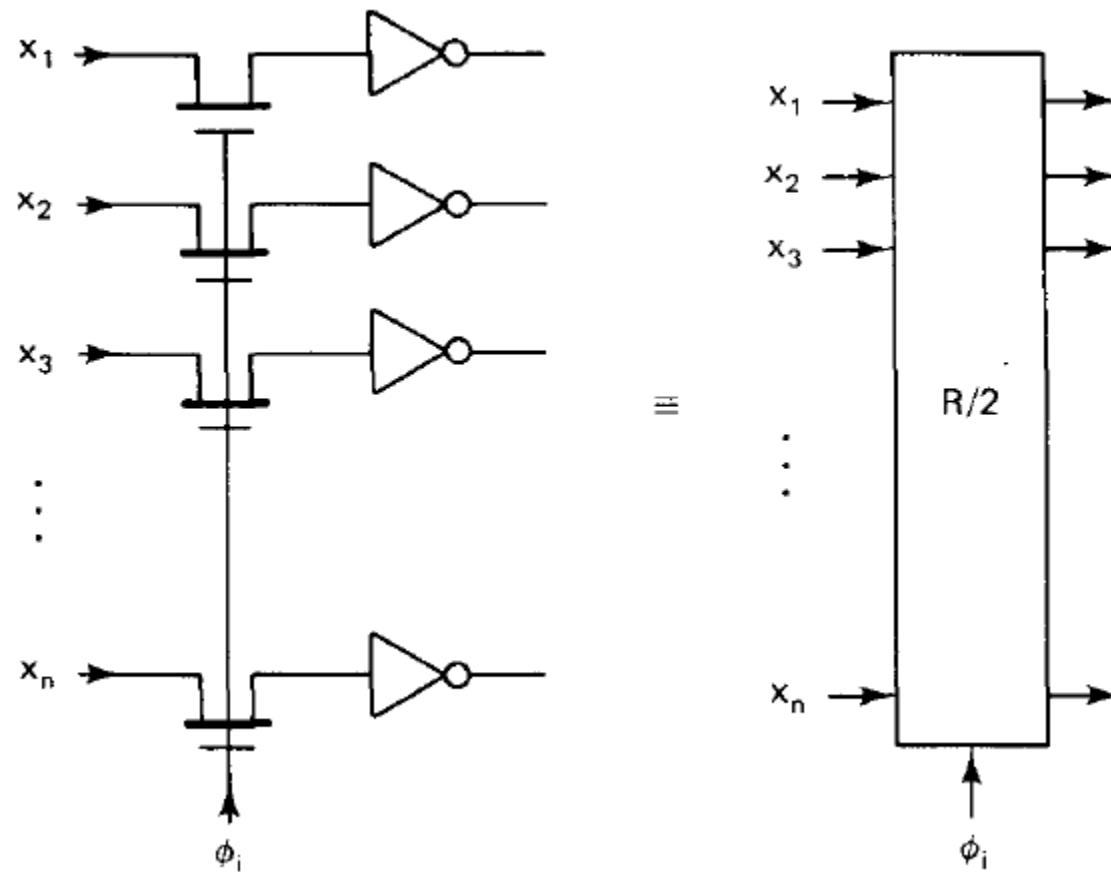


One bit Half-register stage

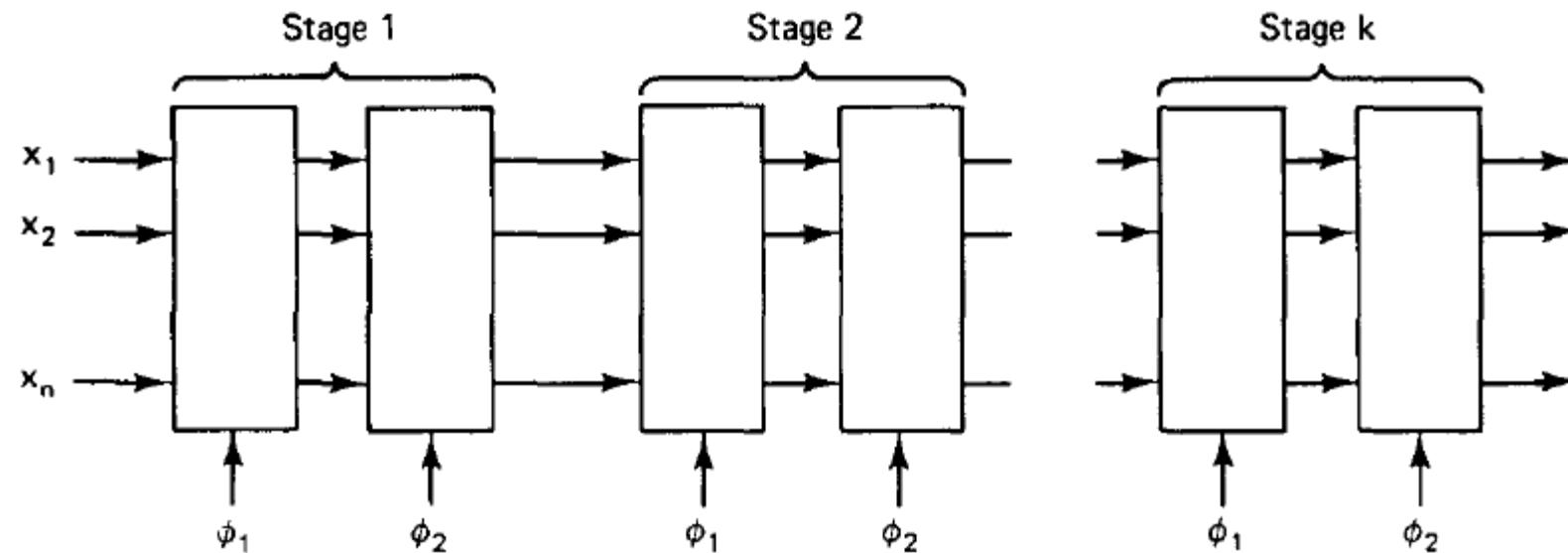


Dynamic shift register for one bit

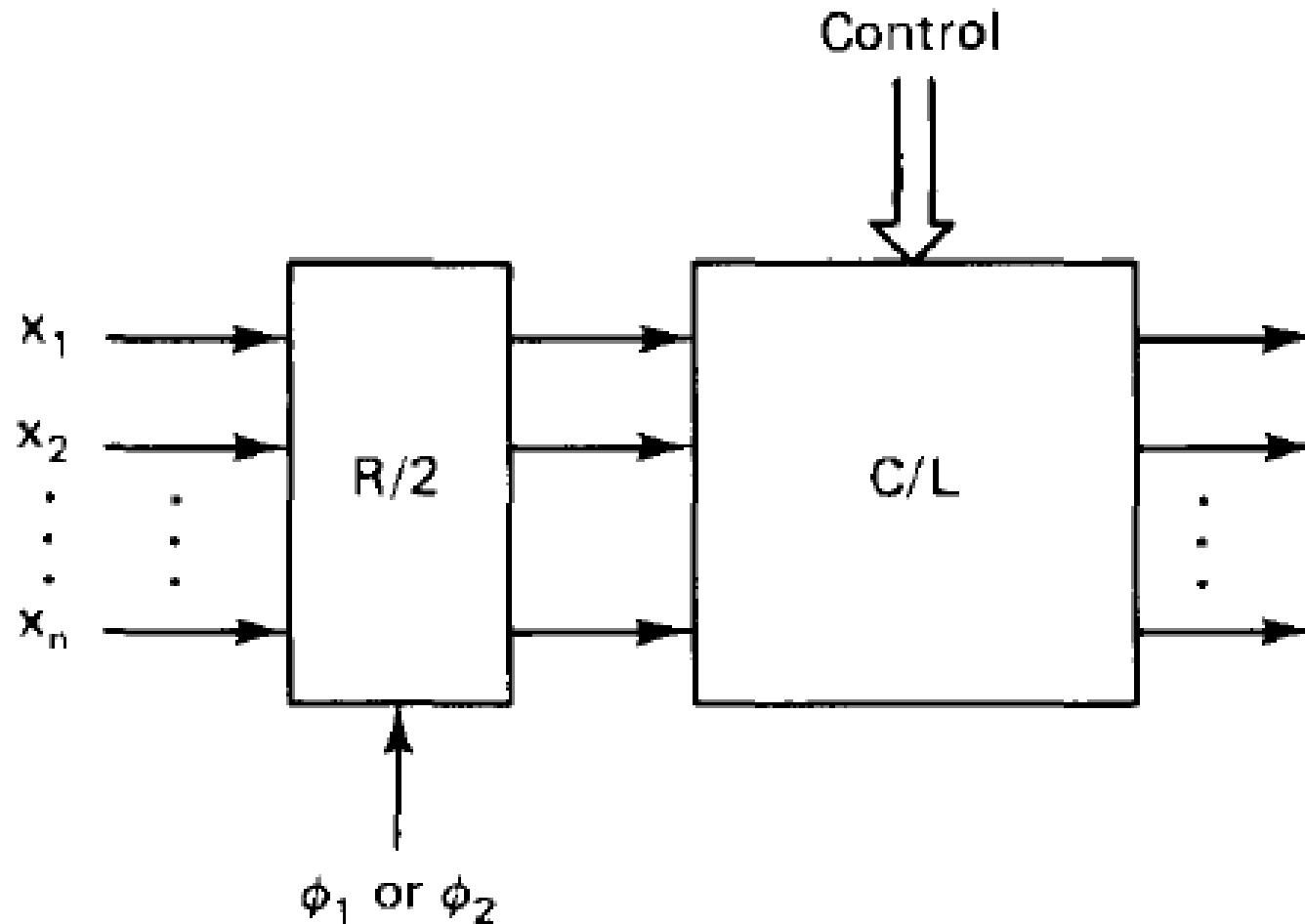
# N-Bit Half Register Stage



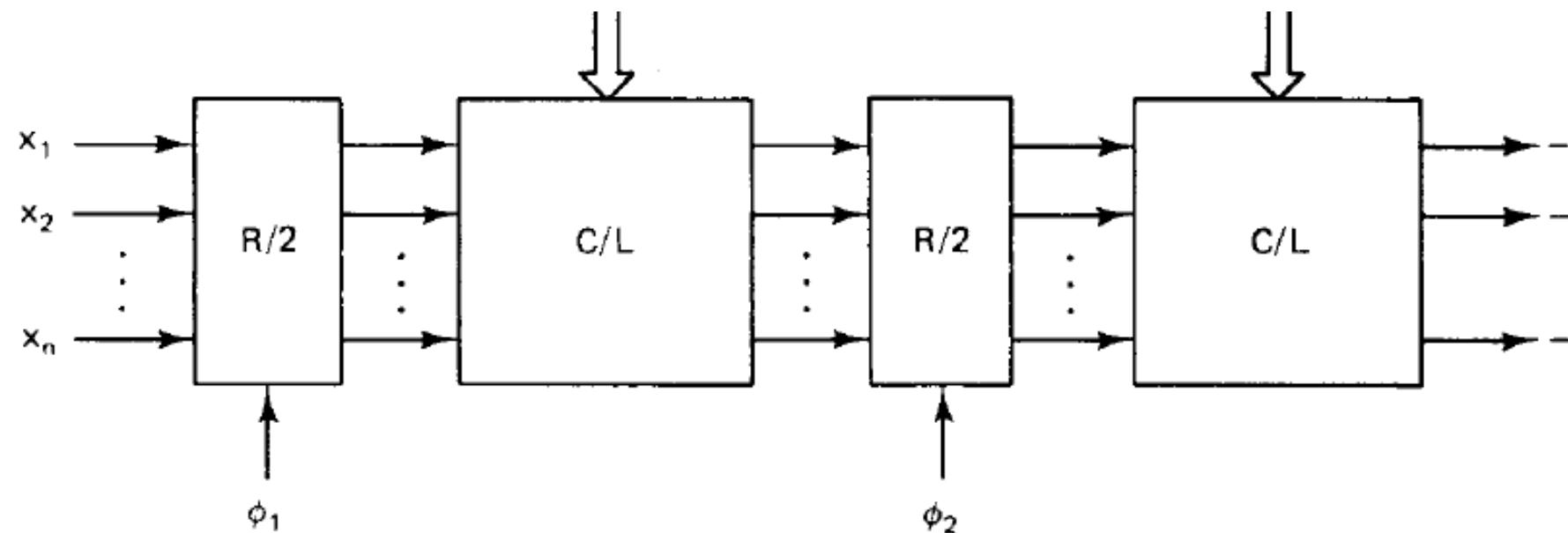
# N-bit shift register K-Stage



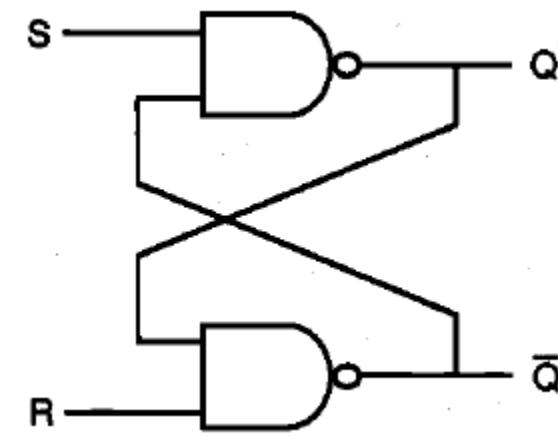
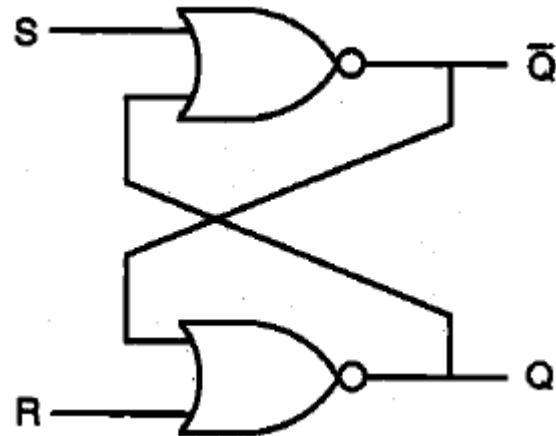
# Half-stage of a data path.



# An $n$ MOS data path



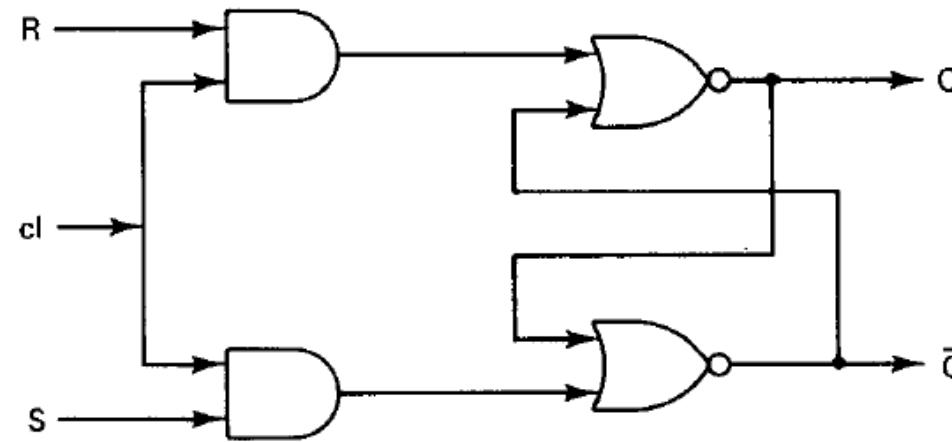
# Static Storage Element



S	R	$Q_{n+1}$	$\bar{Q}_{n+1}$	Operation
0	0	$Q_n$	$\bar{Q}_n$	hold
1	0	1	0	set
0	1	0	1	reset
1	1	0	0	not allowed

S	R	$Q_{n+1}$	$\bar{Q}_{n+1}$	Operation
0	0	1	1	not allowed
0	1	1	0	set
1	0	0	1	reset
1	1	$Q_n$	$\bar{Q}_n$	hold

# Static Storage Element



$S(t)$	$R(t)$	$Q(t + 1)$	$\bar{Q}(t + 1)$
1	0	1	0
0	1	0	1
0	0	$Q(t)$	$\bar{Q}(t)$
1	1	Not allowed	